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# Westinghouse Astronuclear Laboratory

Operational Manual for XE-1 Experimental Controller No. 1 (ETS-1)



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R. R. Bartholomew/N. E. Bush

Circuits Design Equipment Design Electronics and Instrumentation

Ritaisner

R. W. Kaisner, Manager Electronics and Instrumentation

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# Operational Manual for XE-1 Experimental Controller No. 1 Chassis

#### 1. GENERAL

#### 1.1 INTRODUCTION

This operational manual covers the XE-1 Experimental Controller No. 1 Chassis located in Rack 48 and identified by the reference designation 48A6. This chassis contains fuses, test jacks, and the circuit boards for the various subsystem circuits in the chassis. Each subsystem circuit description is complete within the section for that subsystem. Test specifications, photographs, and drawings, which in some instances are common to more than one subsystem, are combined at the end of this manual.

#### 1.2 DESCRIPTION

The chassis consists of a drawer as shown on Drawing 938J912 suitable for mounting in a standard 19" rack. The overall dimensions are 19" wide by 22 1/2" deep by 7" high.

#### 1.2.1 Front Panel

The front panel of the Experimental Controller No. 1 chassis is 19" wide by 7" high. A handle is mounted on each side of the panel. The left handle is equipped with a spring operated mechanical latch to retain the chassis in the closed position in the rack. A button at the upper end of this handle releases the latch when pressed. The handle is equipped with a key lock. The key is removable only when the lock is in the LOCK position. Five Master Specialties Series 70E fuseholders are located along the lower edge of the front panel.

1.2.2 Chassis

The chassis consists of a frame with chassis slides bolted to the sides. A component plate is bolted inside the frame. Printed circuit board guides and connectors for three rows of ten boards are mounted on the component panel. The guides and connectors accomodate 35 pin boards only. The rear center position is occupied by a grounding module.

On the rear of the chassis are two connector plates. On one plate are mounted the 16 pin power connector J1 and a 55 pin signal connector J2. On the second plate, there is mounted one 55 pin signal connector J3. A chassis ground terminal lug is mounted on the chassis frame between the two connector plates.

#### 1.2.3 Component Panel

Bolted across the top of the chassis at the front is the component panel. This panel contains test point jacks and controls for the chassis circuitry.



#### 2. INSTALLATION

#### 2.1 INCOMING INSPECTION

The equipment was carefully inspected both mechanically and electrically before shipment. It should be physically free of mars, dents, or scratches and should be in perfect electrical order upon receipt. To confirm this, the equipment should be inspected for physical damage from transit and tested for electrical performance using the procedures of Section 5. If there is damage or deficiency, repairs should be made before final use.

#### 2.2 MOUNTING

CAUTION: Before installation of the chassis make sure that all power and signals to the rack are tunred off to prevent possible damage to the equipment or injury to personnel.

The chassis is to be mounted in the lower-half of Rack 48 as the sixth drawer from the top. Mount the removable portion of the chassis slides at the desired level of the rack and insert the Experimental Controller No. 1 Chassis in the slides. Refer to Drawing 938J912 for mounting dimensions and construction details of the chassis, panel, and connectors. Connect the mating cables to the connectors at the rear of the chassis.

2.3 POWER REQUIREMENTS

Power is obtained from external sources and enters the unit through the rearmounted 16-pin connector J1. The following are the nominal voltage and current requirements:

a. 28 VDC at 1 amp

b. +15 VDC (to 1&C Common) at 1/2 amp

c. -15 VDC (to 1&C Common) at 1/2 amp



- d.  $+10 \vee DC$  (to 1&C Common) at 1/2 amp
- e. -10 VDC (to 1&C Common) at 1/2 amp



#### 3. EXPERIMENTAL TEMPERATURE CONTROLLER CIRCUITS

#### 3.1 DESCRIPTION AND PRINCIPLES OF OPERATION

The Experimental Temperature Controller circuit is mounted on two printed circuit boards. These boards are located toward the front of the chassis in the left-hand row on the component plate. From front to rear, the circuit boards are:

- 1) A1 Temperature Error 910E314G01
- 2) A2 Temperature Controller 910E315G01

Selected test points are connected to test jacks mounted on the component panel at the top front of the chassis.

The Experimental Temperature Controller is a two stage circuit similar to the Temperature Controller circuit in the Log Power and Temperature Controller Chassis 48A 1, but with a different compensation network. The transfer function for the Experimental Temperature Controller is:

$$\frac{\Theta_{DD}}{T_{D} - T_{M}} = -1.80 \quad \frac{(1+S/.02) \quad \left[\bar{1}+1.4 \quad (S/.223) + (S/.223)^{2}\right]}{(1+S/.0045) \quad (1+S/5)^{2} \quad (1+S/62.8) \quad (1+S/200)} \quad \sqrt{\sqrt{1+S/200}}$$

where  $\Theta_{DD}$  is the control drum velocity demand in volts,  $T_D$  is the temperature demand signal in volts and  $T_M$  is the temperature measured signal in volts. The scaling is:  $\Theta_{DD} = 5$  degrees per second per volt;  $T_D = 450^{\circ}$ R per volt and  $T_M = 450^{\circ}$ R per volt. A third input is provided for signals from the Frequency Analyzer where 15 vp-p signals are provided. These signals are divided to provide a signal equivalent to  $100^{\circ}$ R p-p.

The  $T_D^{(+)}$  and  $T_M^{(-)}$  signals are buffered signals from the Log Power and Temperature Controller Chassis 48A1 and the Frequency Analyzer signal is obtained from the Frequency Analyzer 01RA2 through the Printout Switching Chassis 01RA3. The output from



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the Experimental Controller circuit,  $\Theta_{DD'}$  is applied to the Log Power and Temperature Controller integrator circuit through relay contacts.

Relays A2K1 and A2K2 provide the switching necessary to short the long time constant networks when the circuit is not in used. The DC gain of the circuits under these conditions is 0.415 volt/volt. The shorts are removed and the output of the Experimental Controller circuit is connected to the Log Power and Temperature Controller Chassis when temperature control and experimental control are selected at the console.

#### 3.2 CPERATION

After the chassis has been installed and tested in accordance with the applicable sections of the Test Specification and Procedure, no further adjustments are required.

## 3.3 MAINTENANCE

## 3.3.1 Preventive Maintenance

The equipment is designed so that no special maintenance procedures are required other than the normal good housekeeping rules used for similar type electronic equipment.

#### 3.3.3 Corrective Maintenance

Major corrective maintenance is performed at the factory or by a Westinghouse field representative. Alignment and replacement of obviously faulty components may be performed locally by a skilled technician. There are no specially selected or matched components used, therefore, components may be replaced by locally available parts of identical value and tolerance.

If there is any apparent or suspected failure or improper functioning of the equipment, the equipment should be checked-out in accordance with the Test Specification and Procedure.



#### 3.4 TEST SPECIFICATIONS AND PROCEDURES

#### 3.4.1 Chassis Tests

T-711889 - XE-1 Experimental Controller No. 1 (ETS-1)

T-711889-5 - Functional Tests for Temperature Controller Circuit

### 3.4.2 Printed Circuit Board Tests

T-711889-3 - Temperature Controller (910E315G01)

T-711889-4 - Temperature Error Amplifier (910E314G01)

#### 3.5 DRAWING LIST

- 938J912 Experimental Controller No. 1
- 938J913 Schematic Diagram-Experimental Controller No. 1
- 938J914 Wiring Diagram-Experimental Controller No. 1
- 910E314 Temperature Error Amplifier
- 910E315 Temperature Controller
- 979D442 Fuseholder, Driven Indicator

#### 3.6 PHOTOGRAPHS

- Figure 1 Experimental Controller No. 1
- Figure 2 Temperature Error Amplifier
- Figure 3 Temperature Controller

#### 4. DRUM OVERRIDE

#### 4.1 GENERAL

This section contains the general description, theory of operation, alignment procedures, maintenance and repair data for the Drum Override equipment.

#### 4.1.1 Description

The Drum Override equipment in the Experimental Controller No. 1 Chassis is comprised of four plug-in printed circuit modules as listed below:

(1)	Α3	-	Rate	Limited	Tracking	Amplifier
-----	----	---	------	---------	----------	-----------

- (2) A4 Comparator/Relay Driver/Buffer
- (3) A5 Relay Module
- (4) A6 Relay Module
- (5) A7 Buffer Amplifier

The component parts for the modules are mounted on printed circuit boards measuring 4.5 inches wide and 4.7 inches high. The 35 pin connector on each board mates with a 35 pin socket in the Experimental Controller No. 1 Chassis. Location of the modules in the Experimental Controller is shown in the photograph of Figure 1 and also on the Assembly Drawing 938J912.

#### 4.1.2 Functional Design Specifications

The Drum Override has been designed to conform to the following electrical and functional specifications.

4.1.2.1 The Buffered Drums Demand is a zero to +10 volt buffered signal from the Power and Temperature Controller Chassis (R48).

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4.1.2.2 The Manual Drums Position Demand is a 0 to +10V signal.

4.1.2.3 The Drums Override Threshold Set is a 0 to -10V signal with scaling to engine units of  $2^{\circ}$ /volt.

4.1.2.4 Reactor Auto Start Exponential Setpoint is a 3.34V to 6.67 volt signal scaled to 18°/volt.

4.1.2.5 Drum Override Active/Bypass 0 VDC input gives active condition, and +28VDC gives bypass condition.

4.1.2.6 Drum Override Reset. A +28V signal resets the override.

4.1.2.7 Engine Reset. A +28V signal resets the rate clamp.

4.1.2.8 Manual Drums Position Demand - Positive 0-10VDC signal scaled to 18<sup>°</sup>/volt in engine units.

4.1.2.9 Tracking Circuit Time Constant - 0.1 seconds in Startup Mode and 2 seconds in Startup Completed Mode.

4.1.2.10 Rate limited max. velocity is defined by the rate clamp setpoint and is adjustable over the range  $.5 < \Theta_{set} < 3^{\circ}/sec. \pm 0.1^{\circ}/sec.$  in engine units. 4.1.2.11 Drums Demand  $\Theta_{T}$  Rate Scaling is 3 volts/degree/sec.

4.1.2.12 Outputs

(a) Drums Override Position Demand. Signal range
 from -10 to 0 volts and is the sign inverted Manual Drums Position Demand with scaling of
 18<sup>o</sup>/volt.

(b) Manual Drums Follow-Up Demand. Signal ranges from 0 to +10 volts, and is the output of the rate-limited tracking circuit.



(c) Drums Error Meter. Buffered BUFFERED DRUMS DEMAND Signal 0 to +10V.

(d) Drums Override Normal/Operate. In OPERATE position switch turns on to apply -15 volts to normal/operate relay on Power and Temperature Controller Chassis.

(e) Drums Override Operate Latch. Provides latching action for normal/operate relay using a contact closure on the normal/operate relay.

(f) Drums Override Active Indicate. Provides +28 VDC signal to the operate status indicator. The signal defines the simultaneous de-energized condition of the Drums Override Active/Bypass relay and energized condition of the Rate Clamp Activate relay.

(g) Drums Override Bypass Indicate. Provides +28
 VDC signal to the bypass indicator. The signal defines the energized condition of the Drums
 Override Active/Bypass relay.

4.2 INSTALLATION OF OVERRIDE

4.2.1 Incoming Inspection

The equipment was carefully inspected both mechanically and electrically before shipment. It should be physically free of mars, dents, or scratches and should be in perfect electrical order upon receipt. To confirm this, the equipment should be inspected for physical demage from transit and tested for electrical performance using the procedures of Section 5. If there is damage or deficiency, repairs should be made before final use.



## 4.2.2 Mounting

CAUTION: Before installation of the circuit boards make sure all power and signals to the chassis are turned off to prevent possible damage to the equipment or injury to personnel.

The circuit board (Module A3) is to be mounted in the front of the chassis as shown on Drawing 938J912. Circuit Boards A4, A5, A6, and A7 are located adjacent to the rear of A3.

#### 4.2.3 Power Requirements

Power is obtained from external sources brought into the chassis and enters the unit through the 35-pin connector at the bottom of the board. The following are the nominal voltage and current requirements:

(a)	+15VDC (to I & C Common) at .02 amp
(b)	-15VDC (to I & C Common) at .02 amp
(c)	-10VDC (to I & C Common) at .02 amp

#### 4.3 THEORY OF OPERATION

The following description is with reference to Schematic Drawing 938J913.

The Drum Override consists of a rate limited tracker and threshold comparator. The rate limited tracker follows the control drum position demand with the constraint that the rate of change of the tracking signal cannot exceed a preset positive rate. The rate limit is adjustable locally from 0.5 to 3.0 deg/sec (nominally set for 1.25 deg/sec). The difference between the demand control drum position and the tracked drum position demand is compared to a preset setpoint in an error detecting circuit. If the demanded control drum position exceeds the tracked position demand by the setpoint, the drum demand is switched

from the output of the power and temperature controller chassis to the control drum position demand pot. The setpoint is adjustable from 0 to 20 degrees. (Nominally set at 8.5 degrees.) The output of the tracker also drives the control drum position demand pot followup. The detailed circuit description follows.

#### 4.3.1 Rate Limited Tracking Amplifier

The Rate Limited Tracking Amplifier is comprised of two amplifiers, A1 (a linear amplifier), the other in cascade, A2 (an integrating amplifier). By means of negative feed-back to the + summing junction of Amplifier A1, a unity gain output from Amplifier A2 is obtained. Also, because Amplifier A2 is an integrator, the output of Amplifier A1 is proportional to the velocity or differentiated tracking signal,  $\Theta_{T}$ . The transfer function from the input,  $\Theta_{D}$ , to output,  $\Theta_{T}$ , is given by, for startup mode,

$$\frac{\Theta_{T}(S)}{\Theta_{D}(S)} = \frac{1}{1+RCS} = \frac{1}{1+Q_{T}IS}$$

where RC is Module A3A2 reciprocal gain in the startup mode; and for startup completed mode,

$$\frac{\Theta_{T}(S)}{\Theta_{D}(S)} = \frac{1}{1 + RCS} = \frac{1}{1 + 2S}$$

where RC is Module A3A2 reciprocal gain in the startup completed mode.

The output of Amplifier A2 is limited to 8.9 volts or 160<sup>0</sup> in engine units by means of Diode CR1 and adjustment pot R11. Zener Diode CR2 provides low impedance coupling to the amplifier output to enhance the clamping action.



The output of Amplifier A1,  $\Theta_T$ , is related to the input,  $\Theta_D$ , by the transfer function, for startup mode

 $\frac{\Theta_{T}(S)}{\Theta_{D}(S)} = \frac{-RCS}{1+RCS} = \frac{-25.5S}{1+0.1S}$ 

and for startup completed mode

θ <sub>T</sub> (S)	=		<b>-</b> 52.1S
θ <sub>D</sub> (S) <sub>SM</sub>		1+RCS	]+2S

The full scale output of -10 volts corresponds to a tracker velocity of  $71^{\circ}$ /second in engine units, in the startup mode. In the startup completed mode the maximum positive velocity is set by the diode clamp, CR3, and pot R1 on the component panel, which provides for a clamp setpoint variable from 0.5 to  $3^{\circ}$ /sec (engine units) corresponding to output voltage range from 1.5 to 8.7 volts. The change in gain is accomplished by switching relay contacts A5K1A across resistors R5, R6, and R7.

#### 4.3.2 Comparator/Relay Driver/Buffer

4.3.2.1 General

This card is comprised of two comparator amplifier, A1 and A2; two relay driver transistors, Q1 and Q2; and an inverting amplifier, A3.

The output of Amplifier A1 will be about 0.5 volts more positive than the AUTO STARTUP EXPONENTIAL SET input when the BUFFERED DRUMS DEMAND,  $\Theta_{D}$ , is smaller, because Diode CR1 will be in forward conduction. When the  $\Theta_{D}$  input is



larger, Diode CR1 operates in its Zener region with a drop of about 13 volts across it. The amplifier output voltage will be negative by the difference between the 13 volt Zener voltage and the positive input voltage to the + input point, which may be from 3.3 volts to 6.7 volts. Diode CR1 thus enables Amplifier A1 to operate between two stable states, with the amplifier operating in its active region at all times. This assures the speed of response of the comparator circuit. Input resistors R2 and R3 provide isolation between the inputs and the amplifier.

4.3.2.3 Relay Driver Q1. Transistor Q1 provides a switching action, to energize RATE CLAMP ACTIVATE relay A5K1 when the output of Comparator A1 goes negative. Resistor R4 provides base current drive to Transistor Q1 to hold the Collector-Emitter voltage saturated. Diode CR2 limits the base to emitter voltage on Transistor Q1 to a safe value when the comparator output voltage is positive.

4.3.2.4 Comparator Amplifier A2. The output of the Tracking Amplifier,  $\Theta_{T}$ , is compared differentially with the BUFFERED DRUMS DEMAND,  $\Theta_{D}$ , at the plus and minus inputs, respectively, of Comparator Amplifier A2.

The DRUMS OVERRIDE THRESHOLD SET POINT is combined with the  $\Theta_D$  input signal in the resistor network comprised of resistors R5, R7, and R10. Up to 1.11 volts, or 20° in engine units, can be subtracted from the  $\Theta_D$  signal at the comparator amplifier minus input. The set point is adjustable at the Setup Panel 01-L. When the combined signal exceeds (larger positive voltage) the Tracking Amplifier output,  $\Theta_T$ , the output of Amplifier A2 will switch from a positive voltage output corresponding to Normal Mode, to a negative output voltage corresponding to Operate Mode. In the Normal Mode the output of Amplifier A2 is determined by the forward voltage drop across Diode CR3 plus



the voltage at the Amplifier A2 + input. The + input voltage is the Tracking Amplifier output,  $\Theta_T$ , reduced by the voltage divider comprised of Resistors R6 and R9. In the Operate Mode the output of Amplifier A2 is a negative voltage equal to the difference between the zener voltage of Diode CR3 and the voltage at the + input.

4.3.2.5 Relay Driver Q2. Transistor Q2 provides a switching action to energize the DRUMS OVERRIDE NORMAL/OPERATE relay connected to Pins J25 and J2P from the Power/Temperature Controller Chassis. Energization occurs when the output of Amplifier A2 switches to negative output voltage. Resistor R11 provides base current to drive Transistor Q2 to hold the collector emitter voltage saturated.

4.3.2.6 Buffer Amplifier A2. Input signal to the Buffer Amplifier A3 is the MANUAL DRUMS POSITION DEMAND which is inverted to supply an output DRUMS OVERRIDE POSITION DEMAND signal of negative polarity.

#### 4.3.3 Relay Module A5

#### 4.3.3.1 General

This Module provides two 4PDT relays; one with a 15VDC coil, K1, and the other with a 28VDC coil, K2. Each coil is shunted by a silicon diode to prevent large voltage transients across the coil on de-energization.

4.3.3.2 Rate Clamp Activate Relay K1

Coil of Relay K1 is energized when Transistor Q1 switches into conduction. The closure of the NO (Normally Open) contact K1A couples the output of amplifier A1 on Module A3 to the rate limit clamp Diode A3CR3 through Resistor A3R4, thus limiting the voltage applied to Integrator A3A2 to the value of the SET POINT



on Diode A3CR3. The opening of NC (Normally Closed) contact K1B adds Resistors A3R6, and A3R7 in series with Amplifier A3A2 input. The closure of NO contact K1B locks up Relay K1 so that it remains energized until reset by opening of Contacts A6K2A. Closure of NO Contact K1C provides a +28VDC DRUMS OVERRIDE ACTIVE INDICATE output signal at Connector Pin J2-M.

# 4.3.3.3 Drums Override Active/Bypass Relay K2

The coil of Relay K2 is energized by +28VDC input to Connector Pin J2-DD, DRUMS OVERRIDE ACTIVE/BYPASS. Operation of NC Contact A5K2A prevents operation of Rate Clamp Activate relay by interrupting the -15V supply voltage. The closure pf MP Cpmtact K2B provides a +28V DRUMS OVERRIDE ACTIVE INDICATE output signal at Pin J2-N.

# 4.3.4 Relay Module A6

4.3.4.1 General

This module provides two 4PDT relays; both have 28VDC coils. Each coil is shunted by a silicon diode to prevent large transients across the coil on deenergization.

# 4.3.4.2 Drums Override Reset Relay, K1

The coil of Relay K1 is energized when a +28VDC DRUMS OVER-RIDE RESET signal is received at Connector Pin J2-HH. Operation of NC Contact K1A de-energizes the DRUMS OVERRIDE NORMAL/OPERATE relay returning the Drums Override to Normal condition.



# 4.3.4.3 Engine Reset Relay, K2

Relay coil K2 is energized by a +28VDC ENGINE RESET input s ignal at Connector Pin J2-<u>U</u>. Operation of NC Contact K2A de-energizes the RATE CLAMP ACTIVATE relay.

#### 4.4 OPERATION

#### 4.4.1 General

After installing the Drum Overrides Modules in the Experimental Controller No. 1 Chassis, a mechanical and electrical checkout should be made. Controls, adjustments, and operational test procedures follow here.

#### 4.4.2 Overrides Controls - Operational and Semi-Permanent

Amplifier zero alignment controls and other special circuit alignment controls are located on the individual overrides modules. One control, RATE CLAMP ADJUST, is located on the right rear of the Component Panel of the Experimental Controller No. 1.

# 4.4.3 Test Points

Voltages representing functional quantities involving inputs, outputs and system setpoints can be measured at test points located on the left side of the Component Panel of the Experimental Controller No. 1 Chassis. These are designated as follows:

TP13	RATE CLAMP
TP14	Θ <sub>D</sub> (+)
TP15	$\Theta_{D}$ rate
TP16	θ <sub>T</sub> (+)
TP17	O∨RD SET PT
TP18	expon set



TP19	man demand
TP20	OVRD DEMAND

Additional test points for local measurements are located on the modules.

#### 4.4.4 Operational Checkout

4.4.4.1	Test Equipment Needed			
	(1)	Ohmmeter, Model 269 or equal		
	(2)	Digital Voltmeter, Hewlett–Packard 3440A or equal		
	(3)	Jumpers and Test Leads		
4.4.4.2	Mechanico	I Checkout		

Before application of power for the electrical checkout, examine

gear carefully for mechanical rigidity of all mounted components, connectors, test points, knobs, and like.

#### 4.4.3 Electrical Checkout

Turn on power and allow equipment to warmup for at least 30 minutes.

Checkout in accordance with Experimental Controller No. 1 Checkout Procedure (see Appendix A).

#### 4.4.5 Alignment Procedures

Place the module to be aligned on the extender board where necessary to reach pots adjusted from side.

#### 4.4.5.1 Rate Limited Tracking Amplifier, A3, Alignment

Adjust Amplifier A1 offset to zero. Jumper Test Points TP3 to TP1, and TP8 to TP1 on A3. Adjust the voltage offset pot for minimum output (< 1mv.) at



Test Point A3TP6.

Adjust Amplifier A2 offset to zero. Remove jumper between Test Points A3TP8 and A3TP1. Jumper A3TP5 to A3TP8 and A3TP4 to A5TP1. Adjust offset pot on Amplifier A2 for minimum output (<10mv.) at Test PointA3TP8. Remove jumpers and test leads and replace Module A5.

# 4.4.5.2 Comparator/Relay Driver/Buffer A4 Alignment

Adjust Amplifier A1 offset to zero. Jumper Test Points A4TP2 to A4TP3 and A4TP7 to A4TP1 and adjust the voltage offset for minimum output ( < Imv.) at Test Point A4TP3. Remove jumper.

Adjust Amplifier A2 offset to zero. Jumper Test Point A4TP6 to A4TP1 and A4TP2 to A4TP5 and adjust the voltage offset for minimum output (<Imv $_{\circ}$ ) at Test Point A4TP5. Remove jumper.

Adjust Amplifier A3 offset to zero. Jumper Test Point A4TP9 to A4TP1. Adjust the voltage offset for minimum output (  $\leq 1$ mv.) at Test Point A4TP8. Remove jumper.

Set Rate Clamp Adjust pot on component panel to desired setting.

The Drum Override is ready for use after above adjustments have

been completed. Remove meter test leads from test jacks and close the drawer.

4.5 MAINTENANCE

4.5.1 Preventive Maintenance

The equipment is designed so that no special maintenance procedures are required other than the normal good housekeeping rules used for similar type electronic equipment.



## 4.5.2 Corrective Maintenance

Major corrective maintenance is performed at the factory or by a Westinghouse field representative. Alignment and replacement of obviously faulty components may be performed locally by a skilled technician. There are no specially selected or matched components used, therefore, components may be replaced by locally available parts of identical value and tolerance.

If there is any apparent or suspected failure or improper functioning of the equipment, the equipment should be checked-out in accordance with the Test Specification and Procedure.

# 4.6 TEST SPECIFICATION AND PROCEDURE

The proper Test Specification and Procedure is as follows:

4.6.1 Chassis Test

4.7

T-711889-6 Experimental Controller No. 1 - ETS-1, Drum Override Functional Tests

# 4.6.2 Printed Circuit Card Tests

T-711889-1	Comparator/Relay Driver/Buffer (910E312G01)
T-71188 <b>8-</b> 2	Rate Limited Tracking Amplifier (910E313G01B)
T-711883-4	Standard Buffer Amplifier (910E318G02)
T-711883 <b>-</b> 5	Relay Module (979D576G01 & G02)
DRAWING LIST	

- 938J912 Experimental Controller No. 1
- 938J913 Schematic Diagram-Experimental Controller No. 1
- 910E312 Comparator/Relay Driver/Buffer



- 910E313 Rate Limited Tracking Amplifier
- 910E318 Standard Buffer Amplifier
- 979D576 Relay Module, 4PDT
- 979D575 Schematic Diagram, Relay Module 4PDT

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- 980D916 Standard Operational Amplifier
- 980D922 Operational Amplifier

#### 4.8 PHOTOGRAPH LIST

- Figure 4 Comparator/Relay Driver/Buffer
- Figure 5 Rate Limited Tracking Amplifier
- Figure 6 Buffer Amplifier
- Figure 7 Relay Module

#### APPENDIX A



#### WANL-TME-1704

# EXPERIMENTAL CONTROLLER NO. 1 CHECKOUT PROCEDURE

#### 1.0 SCOPE

This document contains the requirements to functionally checkout the modification to the nuclear subsystem control system for the addition of the first experimental controller chassis (WANL Drawing 938J912, schematic diagram WANL Drawing 938J913) which contains the drum override and the low range state programmed temperature controller.

The first experimental controller chassis has been checked at the chassis level at WANL.

These functional tests are designed to be performed at the system level.

### 2.0 APPLICABLE DOCUMENTS

- 2.1 WANL Drawing 938J912 Experimental Controller No. 1
- 2.2 WANL Drawing 938J913 Schematic Diagram Experimental Controller
   No. 1.

#### 3.0 EXPERIMENTAL CONTROLLER NO. 1

The Experimental Controller No. 1 contains two functions; the low range state programmed temperature controller and the drum override.

The low range state programmed temperature controller is that portion of the state programmed temperature controller which is designed to operate between 60 and 150 psia chamber pressure. The full state programmed temperature controller will be contained in Experimental Controller No. 2.

The drum override consists of a rate limited tracker and threshold comparator. The rate limited tracker follows the control drum position demand with the constraint that the rate of change of the tracking signal cannot exceed a preset positive rate. The rate limit is adjustable locally from 0.5 to 3.0 deg/sec (nominally set for 1.25 deg/sec). The difference between the demand control drum position and the tracked

A-1



drum position demand is compared to a preset setpoint in an error detecting circuit. If the demanded control drum position exceeds the tracked position demand by the setpoint, the drum demand is switched from the output of the power and temperature controller chassis to the control drum position demand pot. The setpoint is adjustable from 0 to 20 degrees. (Nominally set at 8.5 degrees.) The output of the tracker also drives the control drum position demand pot followup.

#### 4.0 FUNCTIONAL TEST.

4.1 Low Range State Programmed Temperature Controller

The low range SPTC is checked by placing the system in simulate and ramping the temperature demand. The temperature demand is then stepped from the frequency analyzer.

- 4.1.1 Place the control system in the simulate mode and establish  $T_c = 1100^{\circ}R$  and  $P_c = 60$  psia in normal temperature and pressure control. Verify normal temperature control indication is "ON" Verify experimental temperature control indication is "OFF"
- 4.1.2 Switch to experimental temperature control. Verify experimental temperature control indication is "ON"

Verify normal temperature control indication is "OFF"

- 4.1.3 Ramp to  $T_c = 2000^{\circ}R$  and  $P_c = 150$  psia along normal operating line and allow system to reach steady state condition.
- 4.1.4 Step temperature demand 100°R from frequency analyzing equipment.
- 4.2 Drum Override

The function tests on the drum override calibrate the "Drums Override Threshold Setpoint" potentiometer. A drum roll out is then simulated to check the operation of the circuit.

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- 4.2.1 Set the "Rate Clamp Adjust" pot, R1, in the experimental controller No. 1 chassis for a voltage of 0.177 VDC (1.25°/sec) at TP13.
- 4.2.2 Calibrate the "Drums Override Threshold Setpoint" pot in the following manner:
  - a) Place pot at the "0" position.
  - b) Remove card A3.

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- c) Apply voltage specified in column (2) of Table 1 to TP14.
- d) Increase pot until drum override "operate" indication occurs.
- e) Record pot divisions in Table 1.
- f) Repeat to verify pot setting.
- g) Complete Table 1 in above manner
- h) Replace card A3
- i) Plot curve of degrees versus pot setting.

## TABLE 1

#### DRUMS OVERRIDE THRESHOLD SETPOINT POT CALIBRATION

(1) TRACK ERROR (DEGREES)	(2) VOLTAGE AT TP 14 (VDC)	•	(3) POT DIV
0	0.000		
1.0	<del>0</del> .055	-	
2.0	0.111		
3.0	0.167		
4.0	0.222		
5.0	0.278	*	
6.0	0.333		
7.0	0.389		
8.0 .	0.444		
9.0	0.500		

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# TABLE 1 (Cont.)

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	(1) TRACK ERROR (DEGR	A	(2) DLTAGE T TP 14 (VDC)	(3) POT DIV	
	10.0	•	.555		
	11.0		.611		
	12.0	0.	.667		
-	13.0	0.	.722		
	14.0	0.	,778		
	15.0	0.	.834		
	16.0	0.	.890		-
	17.0	0.	.945		
	18.0	1.	.000		
	19.0	1.	,055		
ĩ	20.0	1.	.111		
	4.2.3	Place control system	m in simulate with rea	ctor shutdown.	
	4.2.4	Reset drum override	e		
		Verify drum overrid	de active indication is	"OFF"	
		Verify drum overrid	de bypass indication is	"OFF"	
	4.2.5	Perform power auto	-start to 400 watts		
		Verify drum overrid	de active indication is	"ON"	
	4.2.6	Establish $T_c = 1100$	$P_{c}^{o}$ R and $P_{c} = 60$ psia.		
	4.2.7	Switch to experime	ntal temperature conti	ol.	
	4.2.8	Activate reduced g	ain temperature contro	sl.	
	4.2.9	Set "Drums Overrid	de Threshold Setpoint"	for 1 degree.	
	4.2.10	Step drums +2 degre	ees.		
		Verify drum overrid	de "operate" indicatio	n is "ON"	
	4.2.11	Remove drum step			
	4.2.12	Verify drums error r	meter on CTE console	is zero	
	4.2.13	Reset Drum override	e		

# Astronuclear Laboratory

WANL-TME-1704

	Verify drum override "operate" indication is "OFF".
	Verify drum override "normal" indication is "ON".
4.2.14	Scram the system.
	Verify drum override "active" indication is "OFF".
	Verify drum override "bypass" indication is "OFF".
<b>4.2.1</b> 5	Bypass the drum override
	Verify the drum override "active" indication is "OFF"
	Verify the drum override "bypass" indication is "ON"

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# T-711889

# ACCEPTANCE TEST SPECIFICATION AND PROCEDURE

#### XE-1 Experimental Controller No. 1 ETS-1

# 938J912G01

DATE:

September, 1967

holorica 9/7/6/

Circuits Design Equipment Design

Date

9/ 7/67

Supervisor, Circuits Design Date Equipment Design

10-11-67

Guality Engineering

Date

C. C. Marc

Control Systems Engineering Date

INFORMATION CATEGORY

Inclass 4/1/67 •

Authorized Classifier Date

APPROVED BY:

**PREPARED BY:** 



# T-711889 ACCEPTANCE TEST SPECIFICATION AND PROCEDURE XE-1 Experimental Controller No. 1 ETS-1 938J912G01

#### 1. SCOPE

This document contains the requirements for the acceptance testing of the XE-1 Experimental Controller No. 1 Chassis.

## 2. REQUIREMENTS

2.1 The acceptance test shall consist of a <u>Visual Examination</u> (to be performed by Quality Control) and a <u>Functional Test</u> (to be performed by Electronics and Instrumentation and witnessed by Quality Control).

2.2 The acceptance test shall be performed in the order of and as specified in the procedure. Discrepancies found during the visual examination shall be corrected and reinspected before performing the functional test. Failure or inability to obtain a required measurement during formal functional testing shall result in establishing a "hold" on the test. The failure or inadequacy shall be recorded by Quality Control and shall be reviewed by the WANL Engineering Review Board (ERB). The equipment shall be repaired and sections of the test repeated as determined by the ERB. Visual examination shall be performed on the reworked or repaired areas before resuming testing.



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#### 3. APPLICABLE DOCUMENTS

3.1	Drawing	938J912 -	Experimental	Controller No.	1
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- 3.2 Drawing 938 J913 Schematic Diagram, Experimental Controller No. 1
- 3.3 Drawing 938J914 Wiring Diagram, Experimental Controller No. 1

#### 4. EQUIPMENT REQUIRED

- 4.1 +15+.05 VDC source with +0.05% regulation and 1 mv. max. ripple
- 4.2 -15+.05 VDC source with +0.05% regulation and 1 mv. max. ripple
- 4.3 0 to +10 VDC signal source with .01% resolution and 1 mv. max. ripple
- 4.4 0 to -10 VDC signal source with .01% resolution and 1 mv. max. ripple

4.5 +28+1VDC source with +1% regulation and 1 volt max. ripple

- 4.6 Model 269 Simpson Ohmmeter or equal
- 4.7 Digital Voltmeter H-P 3440A or equal

4.8 Set of equipment to measure frequency response and phase shift between .001 cps and 50 cps. (Weston-Boonshaft and Fuchs DA410 or equal)



#### T-711889

### 5. VISUAL EXAMINATION

The equipment under test shall be presented in its final form together with the applicable schematic and assembly drawing. The visual examination shall consist of the following parts:

### 5.1 WORKMANSHIP, ASSEMBLY, AND FIT

The inspector shall inspect the equipment for workmanship to WANL requirements, and to assure that the overall board is of the proper dimensions per the assembly drawing.

Westinghouse Drawing Number\_\_\_\_\_Rev.

Workmanship OK

# 5.2 MATERIALS, PARTS, AND FINISHES

The equipment shall be inspected to assure that the materials, parts, and finishes are in accordance with the applicable assembly drawings. Incoming inspection records on materials, parts, and finishes shall be utilized to determine conformance to the assembly drawings where possible.

Materials OK \_\_\_\_\_

5.3 MARKING

The markings on the equipment shall be inspected to ensure conformance to the applicable drawings and to assure that they are acceptable as to permanence and readibility.

Marking OK



# T-711889

# 6. FUNCTIONAL TESTS

The Temperature Controller and NSS Drum Override Circuits are separate circuits which operate independent of each other and, therefore, are approved and tested separately.

- 6.1 TEMPERATURE CONTROLLER USE T-711889-5
- 6.2 NSS DRUM OVERRIDES USE T-711889-6



# ACCEPTANCE TEST SPECIFICATION AND PROCEDURE

Experimental Controller No. 1

Comparator/Relay Driver/Buffer

910E312G01

DATE:

September, 1967

Such 9/20/67

Circuits Design Equipment Design

Date

20/07

Supervisor, Circuits Design Date Equipment Design

Ef m. Quarde 9-26-67

Quality Engineering

Date

C.C

Control Systems Engineering Date

INFORMATION CATEGORY

9/20/(7

Authorized Classifier Date

APPROVED BY:

**PREPARED BY:** 



# T-711889-1 ACCEPTANCE TEST SPECIFICATION AND PROCEDURE Experimental Controller No. 1 Comparator/Relay Driver/Buffer 910E312G01

# 1. SCOPE

This document contains the requirements for the acceptance testing of the Comparator/Relay Driver/Buffer Board prior to incorporating the board into the Experimental Controller No. 7 Chassis 938J912G01.

# 2. REQUIREMENTS

2.1 The acceptance test shall consist of a <u>Visual Examination</u> (to be performed by Quality Control) and a <u>Functional Test</u> (to be performed by Electronics and Instrumentation and witnessed by Quality Control).

2.2 The acceptance test shall be performed in the order of and as specified in the procedure. Discrepancies found during the visual examination shall be corrected and reinspected before performing the functional test. Failure or inability to obtain a required measurement during formal functional testing shall result in establishing a "hold" on the test. The failure or inadequacy shall be recorded by Quality Control and shall be reviewed by the WANL Engineering Review Board (ERB). The equipment shall be repaired and sections of the test repeated as determined by the ERB. Visual examination shall be performed on the reworked or repaired areas before resuming testing.



# 3. APPLICABLE DOCUMENTS

- 3.1 Drawing 910E312 Comparator/Relay Driver/Buffer
- 3.2 Drawing 928F953 Printed Circuit Board

### 4. EQUIPMENT REQUIRED

- 4.1 +15+.05 VDC source with +0.05% regulation and 1 mv. max. ripple
- 4.2 -15+.05 VDC source with +0.05% regulation and 1 mv. max. ripple
- 4.3 Positive signal source, variable 0-10 VDC with .01% resolution and 1 mv. max.

ripple

4.4 Negative signal source, variable 0-10 VDC with .01% resolution and 1 mv. max. ripple

4.5 Model 269 Simpson Ohmmeter or equal

4.6 Digital Voltmeter H-P 3440A or equal

4.7 Oscilloscope, Tektronix 585 or equal

4.8 Signal Generator H-P 241A or equal

4.9 200 Ohm Resistor, 2 Watt



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## T-711889-1

# 5. VISUAL EXAMINATION

The equipment under test shall be presented in its final form together with the applicable schematic and assembly drawing. The visual examination shall consist of the following parts:

# 5.1 WORKMANSHIP, ASSEMBLY, AND FIT

The inspector shall inspect the equipment for workmanship to WANL requirements, and to assure that the overall board is of the proper dimensions per the assembly drawing.

Westinghouse Drawing Number \_\_\_\_\_ Rev.

Workmanship OK

# 5.2 MATERIALS, PARTS, AND FINSIHES

The equipment shall be inspected to assure that the materials, parts, and finishes are in accordance with the application assembly drawings. Incoming inspection records on materials, parts, and finishes shall be utilized to determine conformance to the assembly drawings where possible.

Materials OK \_\_\_\_\_

5.3 MARKING

The markings on the equipment shall be inspected to ensure conformance to the applicable drawings and to assure that they are acceptable as to permanence and readibility.

Marking OK





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#### 6. FUNCTIONAL TESTS

#### 6.1 COMPARATOR A1 AND RELAY DRIVER Q1

#### 6.1.1 Alignment

6.1.1.1 Jumper Test Points TP2 to TP3 and TP7 to TP1 and adjust the voltage offset for minimum output (< 1 mv.) at Test Point TP3. Record offset voltage: \_\_\_\_\_.

#### 6.1.2 Input Balance Check

6.1.2.1 Apply +3.300 volts to Pin 9. Apply the same polarity voltage to Pin 8 and adjust it to make the output voltage of Test Point TP3 change in negative direction. Measure the voltage at Pin 8. It should be 3.300+0.1 volts. Record test result.

Voltage at Pin 8: \_\_\_\_\_ volts.

6.1.2.2 Increase voltage at Pin 8 an amount just sufficient to cause output to reach maximum voltage (where further increase of voltage at Pin 8 does not cause further rapid increase of output at Test Point TP3). Measure and record voltage at Pin 8 and at Test Point TP3. Voltage at Pin 8 should be 3.3  $\begin{array}{c}+0.1\\-0\end{array}$  volts and at TP3(-) 9.1  $\pm$ 0.7 volts.

Voltage at Pin 8: volts.

Voltage at TP3: volts.

6.1.2.3 Subtract voltage at Pin 8 determined in Steps 6.1.2.2 from that determined in Step 6.1.2.1. The difference should be less than 0.1 volts. Record the test result. Difference voltage at Test Point TP8: \_\_\_\_\_\_ volts.

6.1.2.4 Repeat Step 6.1.2.1, except apply voltage at Pin 9 of 6.600 volts. Voltage at Pin 8 should be 6.600+.100 volts. Record test results. Voltage at Pin 8: \_\_\_\_\_\_\_volts.

- 4 -



6.1.2.5 Repeat Step 6.1.2.2, except voltage at Pin 9 shall be 6.600 volts. Voltage measured at Pin 8 should be 6.6+0.1 volts and at Test Point TP3 (-) 5.8+0.7 volts. Voltage at Pin 8: \_\_\_\_\_\_ volts.

Voltage at Test Point TP3: \_\_\_\_\_\_ volts.

6.1.3 Relay Driver Q1 Test

6.1.3.1 Connect the 200 ohm resistor from Pin 31 to (-) 15 VDC. With voltage at Test Point TP3 as in Step 6.1.2.5 voltage measured at Pin 31 should be less than
(-) 0.5 volt. Voltage at Pin 31: \_\_\_\_\_\_ volts.

6.1.3.2 Set voltage at Pin 8 to zero. Voltage measured at Pin 31 should be
(-) 15 volts. Record test result. Voltage at Pin 31: \_\_\_\_\_\_ volts.

6.1.3.3 Measure voltage from base to emitter of Transistor Q1. It should be less than 0.75 volts. Record result. Base-emitter voltage of Q1: \_\_\_\_\_\_ volt. Remove test sources, resistor and meters.

6.2 COMPARATOR A2 AND RELAY DRIVER Q2

6.2.1 Alignment

6.2.1.1 Jumper Test Point TP6 to TP1 and TP2 to TP5 and adjust the voltage offset for minimum output ( < 1 mv.) at Test Point TP5. Record offset voltage:\_\_\_\_\_. Remove all jumpers from points.

6.2.2 Input Balance Check

6.2.2.1 Ground Pin 28 and Pin 24. Apply a negative polarity voltage to Pin 8 and adjust it to make the output voltage of Test Point TP5 change in negative direction. Measure the voltage at Pin 8. It should be <-.01 volt. Record test result.

Voltage at Pin 8: \_\_\_\_\_ volts.



6.2.2.2 Change voltage at Pin 8 in positive direction an amount just sufficient to cause output to reach maximum negative voltage (where further increase of voltage at Pin 8 does not cause further rapid increase of output at Test Point TP5). Measure and record voltage at Pin 8 and at Test Point TP5. Voltage at Pin 8 should be < +.01 volts and at TP5(-) 12.6+0.7 volts.

Voltage at Pin 8: \_\_\_\_\_ volts.

Voltage at TP5: volts.

6.2.2.3 Subtract voltage at Pin 8 determined in Step 6.2.2.2 from that determined in Step 6.2.2.1. The difference should be less than 0.01 volts. Record the test result. Difference voltage at Test Point TP8: \_\_\_\_\_\_\_ volts.

6.2.2.4 Apply (-) 10.00 volts to Pin 24 and observe that output voltage at Test Point TP5 becomes positive. Increase voltage at Pin 8 an amount just sufficient to cause the output voltage at Test Point TP5 to reach maximum. Measure and record the voltage at Pin 8. It should be 1.111+0.1 volts. Voltage at Pin 8: volts.

6.2.2.5 Ground Pin 24 and apply voltage at Pin 28 of +10.00 volts. Apply positive voltage at Pin 8 until output at TP5 starts negative. Voltage at Pin 8 should be 10.00+.05 volts. Record test results.

Voltage at Pin 8: volts.

6.2.2.6 Repeat Step 6.2.2.2, except voltage at Pin 28 shall be +10.00 volts. Voltage measured at Pin 8 should be ≤ 10 mv. more than result in 6.2.2.5 and at Test Point

TP5(-) 7.9+0.7 volts.

Voltage at Pin 8: \_\_\_\_\_ volts.

Voltage at Test Point TP5: volts.

# 6.2.3 Relay Driver Q2 Test

6.2.3.1 Connect the 200 ohm resistor from Pin 30 to (-) 15 VDC. With voltage at Test Point TP5 as in Step 6.2.2.6 voltage measured at Pin 30 should be less than (-) 0.5 volts.

Voltage at Pin 30: volts.

6.2.3.2 Set voltage at Pin 8 to zero. Voltage measured at Pin 30 should be
(-) 15 volts. Record test result voltage at Pin 30: \_\_\_\_\_\_ volts.

6.2.3.3 Measure voltage from base to emitter of Transistor Q2 it should be less than 0.75 volts. Record result. Base emitter voltage of Q2: \_\_\_\_\_\_ volt.

6.3 BUFFER A3 TEST

## 6.3.1 Gain and Linearity Check

6.3.1.1 Ground Pin 35.

6.3.1.2 Adjust the voltage offset for minimum output ( < 1 mv.) at Pin 33. Record offset voltage:

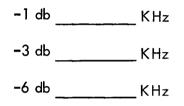
6.3.1.3 Remove ground from Pin 35. Connect the DC voltage source to Pin35. Measure gain and linearity by using input signal at Pin 35 and output at Pin 33. Record

results.	Input VDC	Output VDC
	0	0+.01
	+5	-5+。1
	+10	-10+.2
	<b>-</b> 5	+5+.1
	-10	+10+.2



# 6.3.2 Frequency Response Check

6.3.2.1 Disconnect the voltage source from Pin 35 and connect the function generator. Determine the break frequency of the amplifier by using input Pin 35 and output Pin 33. The break frequency (-3 db point) should be greater than 1000 cps. Record the following frequencies:



6.3.3 Output Noise

6.3.3.1 Remove the function generator. Ground Pin 35 and connect the oscilloscope to Pin 33. The øbserved a-c waveform should be less than ten millivolts peak. Record the value oscilloscope waveform peak at Pin 33: \_\_\_\_\_\_\_mv. Remove jumpers and test leads.

6.4 RESISTANCE AND CONTINUITY CHECKS

6.4.1 Verify continuity between the following points:

TP1 and Pin 3	
TP2 and Pin 8	
TP4 and Pin 24	
TP8 and Pin 33	
TP9 and Fin 35	

6.4.2 Remove Module A2. Measure resistance between TP6 and TP1: \_\_\_\_\_\_ ohms. Value should be 10K+3%.

6.4.3 Remove Module A1. Measure resistance between TP7 and Pin 9:\_\_\_\_\_ ohms. Value should be 100K+3%.



## ACCEPTANCE TEST SPECIFICATION AND PROCEDURE

Experimental Controller No. 1

Rate Limited Tracking Amplifier

# 910E313G01B

DATE:

October, 1967

PREPARED BY:

1/2. Bush 11/24/07

Circuits Design **Equipment Design** 

Date

10/24/67

Supervisor, Circuits Design Date Equipment Design

10:25-1. ty Engineering Date

Control Systems Engineering Date

### **INFORMATION CATEGORY**

hyckassy 10/29/67 Church

Authorized Classifier

Date

APPROVED BY:



# T-711889-2 ACCEPTANCE TEST SPECIFICATION AND PROCEDURE Experimental Controller No. 1 Rate Limited Tracking Amplifier 910E313G01B

# 1. SCOPE

This document contains the requirements for the acceptance testing of the Comparator/Relay Driver/Buffer Board prior to incorporating the board into the Experimental Controller No. 1 Chassis 938J912G01.

# 2. REQUIREMENTS

2.1 The acceptance test shall consist of a <u>Visual Examination</u> (to be performed by Quality Control) and a <u>Functional Test</u> (to be performed by Electronics and Instrumentation and witnessed by Quality Control).

2.2 The acceptance test shall be performed in the order of and as specified in the procedure. Discrepancies found during the visual examination shall be corrected and reinspected before performing the functional test. Failure or inability to obtain a required measurement during formal functional testing shall result in establishing a "hold" on the test. The failure or inadequacy shall be recorded by Quality Control and shall be reviewed by the WANL Engineering Review Board (ERB). The equipment shall be repaired and sections of the test repeated as determined by the ERB. Visual examination shall be performed on the re-worked or repaired areas before resuming testing.



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### 3. APPLICABLE DOCUMENTS

- 3.1 Drawing 910E313 Comparator/Relay Driver/Buffer
- 3.2 Drawing 928F954 Printed Circuit Board

#### 4. EQUIPMENT REQUIRED

4.1 +15+.05 VDC source with +0.05% regulation and 1 mv. max. ripple

4.2 -15+.05 VDC source with +0.05% regulation and 1 mv. max. ripple

4.3 Positive signal source, variable 0-10 VDC with .01% resolution and 1 mv. max.

ripple

4.4 Negative signal source, variable 0-10 VDC with .01% resolution and 1 mv. max. ripple

4.5 Model 269 Simpson Ohmmeter or equal

- 4.6 Digital Voltmeter H-P 3440A or equal
- 4.7 Oscilloscope, Tektronix 585 or equal
- 4.8 Ramp Generator, +0 to 4 volts/sec.
- 4.9 Test Leads and Jumpers
- 4.10 X-Y Recorder, H-P 136A or equal
- 4.11 Recorder, Brush Mark II or equal



#### 5. VISUAL EXAMINATION

The equipment under test shall be presented in its final form together with the applicable schematic and assembly drawing. The visual examination shall consist of the following parts:

5.1 WORKMANSHIP, ASSEMBLY, AND FIT

The inspector shall inspect the equipment for workmanship to WANL requirements, and to assure that the overall board is of the proper dimensions per the assembly drawing.

Westinghouse Drawing Number \_\_\_\_\_ Rev. \_\_\_\_

Workmanship OK

## 5.2 MATERIALS, PARTS, AND FINISHES

The equipment shall be inspected to assure that the materials, parts, and finishes are in accordance with the application assembly drawings. Incoming inspection records on materials, parts, and finishes shall be utilized to determine conformance to the assembly drawings where possible.

Materials OK \_\_\_\_\_

5.3 MARKING

The markings on the equipment shall be inspected to ensure conformance to the applicable drawings and to assure that they are acceptable as to permanence and readibility.

Marking OK \_\_\_\_\_



#### 6. FUNCTIONAL TESTS

6.1 Remove Amplifiers A1 and A2. Make the following resistance checks:

From	<u>To</u>	Ohms	Check
Pin 3	TPI	< 1	
Pin 5	TP2	< 1	
Pin 8	ТРЗ	< 1	
Pin 20	TP4	<1	
Pin 22	TPI	< 1	
Pin 24	TP5	<1.	
Pin 30	Pin 31	< 1	
TP4	TP6	90.9K <u>+</u> 3%	
ТЫ	TP8	1.013M <u>+</u> 3%	
TP5	TP7	36.5K <u>+</u> 3%	

Reinstall Amplifiers A1 and A2.

### 6.2 ALIGNMENT CHECK

6.2.1 Ground Pin 3 and Pin 8. Connect +15VDC to Pin 1 and -15 VDC to Pin 2.

6.2.2 Amplifier A1

Jumper Test Points TP7 to TP8. Ground TP7 and adjust the voltage offset for minimum output ( < 1 mv.) at TP6. Record offset voltage:\_\_\_\_\_. Verify that offset pot > 1/2 tum from ends:\_\_\_\_\_.

6.2.3 Amplifier A2

6.2.3.1 Remove ground from TP8, and remove jumper between TP7 and TP8, Jumper TP4 to TP1, and TP5 to TP8. Adjust the voltage offset for minimum output (< 1 mv.)



at TP8. Record offset voltage: \_\_\_\_\_. Verify that offset pot > 1/2 turn from ends:

6.2.3.2 Apply +10VDC to Pin 8 and adjust pot R11 to give +8.9 volts output at TP8. Record result: \_\_\_\_\_. Verify that pot R11 > 1/2 turn from ends:

6.3 GAIN AND LINEARITY CHECK

6.3.1 Remove ground from Pin 8; remove jumpers from TP4 to TP1, and TP5 to TP8. Measure gain and linearity by using input at Pin 8 and output at

TP8. Record results.

Input VDC	Output VDC
0	0+.01
+2.0	+2.0+.05
+4.0	+4.0+.10
+6.0	+6.0+.13
+8.0	+8.0+.17

#### 6.4 TIME CONSTANT CHECK

6.4.1 Remove 10VDC input from Pin 8. Measure time constant by using input at Pin 8 and output at TP8, using the Oscilloscope.

6.4.2 Startup Completed Mode

6.4.2.1 Apply a positive step voltage of 0.5VDC to Pin 8. Exponential rise of output voltage at TP8 should have a time constant (time to reach 63.2% point) of 2.1+.4 seconds. Record time constant: sec



#### 6.4.3 Startup Mode

6.4.3.1 Jumper TP4 to TP5. Apply a positive step voltage of 0.5VDC to Pin 8. Exponential rise of output voltage at TP8 should have a time constant (63.2% point) of 0.1<u>+</u>.015 seconds. Record time constant: \_\_\_\_\_sec.

# 6.5 AVAILABLE TRACK VELOCITY CHECK

### 6.5.1 Startup Mode

6.5.1.1 Leave jumper connected from TP4 to TP5. Measure available track velocity by using input at Pin 8 and output at TP6.

6.5.1.2 Connect the Ramp Generator to Pin 8 and adjust it to +3.9v/sec. Measure the output on the Recorder. It should be -9.9+.2v. Record result: \_\_\_\_\_.

6.5.1.3 Adjust the Ramp Generator to -3.9v/sec and apply it to Pin 8. Measure the output on the Recorder. It should be +9.9+.2v. Record result:\_\_\_\_\_.

#### 6.5.2 Startup Completed Mode

6.5.2.1 Remove jumper from TP4 to TP5. Set Ramp Generator output to -1/6v/sec, and apply it to Pin 8. Measure the output at TP6 on the Digital Voltmeter. It should be +8.9+.2 volts. Record result:\_\_\_\_\_.

6.5.2.2 Set Ramp Generator output to +1/6v/sec and apply it to Pin 8. Measure the output at TP6 on the Digital Voltmeter. It should be -8.9+.2 volts. Record result:\_\_\_\_\_\_.



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### T-711889-2

### 6.6 RATE CLAMP CHECK

6.6.1 Ground Pin 5. Jumper Pin 4 to Pin 20. Apply a +10V step to Pin 8. Measure voltage at Pin 20 on Digital Voltmeter and rate of change (slope) at TP8 on the X-Y recorder. Record results.

Voltage at Pin 20 should be between 0 to -1VDC:\_\_\_\_\_

Slope at TP8 should be < 19mv/sec:

6.6.2 Remove ground from Pin 5. Apply -10VDC to Pin 5. Apply a +10V step to Pin 8. Measure as in 6.6.1, above, and record results.

Voltage at Pin 20 should be from -10VDC to -11VDC

Slope at TP8 should be >.19V/sec:

6.6.3 Apply voltage to Pin 5 and adjust it to make voltage at TP4 read -3.73 volts when step voltage of +5 volts is applied to Pin 8. Measure voltage at Pin 5. Voltage at Pin 5. should be -3.2+.2V:\_\_\_\_\_. Measure output rate of change at TP8. It should be 69+3mv/sec:\_\_\_\_\_.



# ACCEPTANCE TEST SPECIFICATION AND PROCEDURE

# Experimental Controller No. 1

### **Temperature Controller**

### 910E315G01

DATE:

August, 1967

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Circuits Design Equipment Design

Date

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Supervisor, Circuits Design Date Equipment Design

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Quality Engineering

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Date

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Control Systems Engineering Date

INFORMATION CATEGORY

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Authorized Classifier Date

APPROVED BY:

**PREPARED BY:** 



# T-711889-3 ACCEPTANCE TEST SPECIFICATION AND PROCEDURE Experimental Controller No. 1 Temperature Controller 910E315G01

# 1. SCOPE

This document contains the requirements for the acceptance testing of the Temperature Controller PCB prior to incorporating the board into the Experimental Controller Chassis.

# 2. REQUIREMENTS

2.1 The acceptance test shall consist of a <u>Visual Examination</u> (to be performed by Quality Control) and a <u>Functional Test</u> (to be performed by Electronics and Instrumentation and witnessed by Quality Control).

2.2 The acceptance test shall be performed in the order of and as specified in the procedure. Discrepancies found during the visual examination shall be corrected and reinspected before performing the functional test. Failure or inability to obtain a required measurement during formal functional testing shall result in establishing a "hold" on the test. The failure or inadequacy shall be recorded by Quality Control and shall be reviewed by the WANL Engineering Review Board (ERB). The equipment shall be repaired and sections of the test repeated as determined by the ERB. Visual examination shall be performed on the reworked or repaired areas before resuming testing.



# 3. APPLICABLE DOCUMENTS

- 3.1 Drawing 910E315 Temperature Controller
- 3.2 Drawing 928 F978 Printed Circuit Board
- 3.3 Drawing 947C087 Schematic, Amplifier

# 4. EQUIPMENT REQUIRED

- 4.1 +15+.05 VDC source with +0.05% regulation and 1 mv. max. ripple
- 4.2 -15+.05 VDC source with +0.05% regulation and 1 mv. max. ripple
- 4.3 0 to +10 VDC signal source with .01% resolution and 1 mv. max. ripple
- 4.4 0 to -10 VDC signal source with .01% resolution and 1 mv. max. ripple
- 4.5 Model 269 Simpson Ohmmeter or equal
- 4.6 Digital Voltmeter H-P 3440A or equal
- 4.7 Set of equipment to measure frequency response and phase shift between .001 cps

and 50 cps. (Weston-Boonshaft and Fuchs DA410 or equal)



WANL-TME-1704

## T-711889-3

### 5. VISUAL EXAMINATION

The equipment under test shall be presented in its final form together with the applicable schematic and assembly drawing. The visual examination shall consist of the following parts:

# 5.1 WORKMANSHIP, ASSEMBLY, AND FIT

The inspector shall inspect the equipment for workmanship to WANL requirements, and to assure that the overall board is of the proper dimensions per the assembly drawing.

Westinghouse Drawing Number \_\_\_\_\_ Rev. \_\_\_\_

Workmanship OK

# 5.2 MATERIALS, PARTS, AND FINISHES

The equipment shall be inspected to assure that the materials, parts, and finishes are in accordance with the applicable assembly drawings. Incoming inspection records on materials, parts, and finishes shall be utilized to determine conformance to the assembly drawings where possible.

Materials OK

5.3 MARKING

The markings on the equipment shall be inspected to ensure conformance to the applicable drawings and to assure that they are acceptable as to permanence and readibility.

Marking OK \_\_\_\_\_



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# T-711889-3

# 6. FUNCTIONAL TESTS

# 6.1 RELAY AND RESISTANCE CHECKS

6.1.1 With the relays and amplifier de-energized, make the following resistance measurements using the Simpson Model 269:

From (+)	<u>To (-)</u>	Ohms Required	Ohms Measured
Pin 13	Pin 6	500+10%	
*Pin 6	Pin 13	< 100	
Junction of K1A & C1	Pin 4	> 10 Meg	
Junction of K1A & C1	Pin 3	33.2K <u>+</u> 10%	
Junction of R6 & C6	Junction of R8 & R9	< 1	
Pin 5	Pin 8	>10 Meg	<u></u>
Pin 5	Pin 9	< 1	
Pin 12	Pin 10	>10 Meg	
Pin 12	Pin 11	<1	
Pin 21	Pin 19	1030+10%	
*Pin 19	Pin 21	< 100	
Pin 17	Pin 15	>10 Meg	
Pin 17	Pin 14	< 1	<u></u>
Pin 20	Pin 16	>10 Meg	



WANL-TME-1704

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# T-711889-3

From (+)	<u>To (-)</u>	Ohms Required	Ohms Measured
Pin 20	Pin 18	< 1	
Pin 3	τρι	<1	
Pin 4	TP2	< 1	
Pin 35	ТРЗ	< 1	

\* Use X1 scale on Simpson Model 269.

6.1.2 Energize Relays K1 and K2 from the 28 VDC source and make the following resistance measurements:

From (+)	<u>To (-)</u>	Ohms Required	Ohms Measured
Junction of K1A & C1	Pin 4	1.2Meg <u>+</u> 10%	<u></u>
Junction of K1A& C1	Pin 3	>1 Meg	
Junction of R6 & C6	Junction of R8 & R9	> 1.2 Meg	
Pin 5	Pin 8	< 1	
Pin 5	Pin 9	>10 Meg	
Pin 12	Pin 10	<b>&lt;</b> 1	
Pin 12	Pin 11	>10 Meg	
Pin 17	Pin 15	<1	
Pin 17	Pin 14	>10 Meg	
Pin 20	Pin 18	>10 Meg	
Pin 20	Pin 16	<1	



### 6.2 GAIN AND LIMIT CHECK

6.2.1 Energize Relay K1 from the 28 VDC supply and apply the plus and minus 15 VDC to the board.

6.2.2 Ground Pin 4 and adjust the voltage offset of A1 for minimum output at Pin 35

( < 1 mv.). Record offset voltage: . Remove ground.

6.2.3 Apply a signal to Pin 4 of approximately 1 VDC of either polarity and measure the output at Pin 35 with the DVM. Determine the DC gain and record: (K = 1.80+.036)

6.2.4 Apply positive and negative signals to Pin 4 of sufficient amplitude to measure the output limits at Pin 35 and record the voltage limits.

Positive Limit (4+.5 VDC)

Negative Limit (-4+.5 VDC)

6.3 FREQUENCY RESPONSE CHECK

6.3.1 Run a frequency response between input Pin 4 and output Pin 35 with K1 energized and K2 de-energized. Plot gain in db and phase in degrees on Figure 1. The following tolerances shall be met in the range indicated:

.01 rad/sec<u><</u>W<u><</u>4 rad/sec GAIN<u>+</u>2db from nominal PHASE<u>+</u>10<sup>0</sup> from nominal

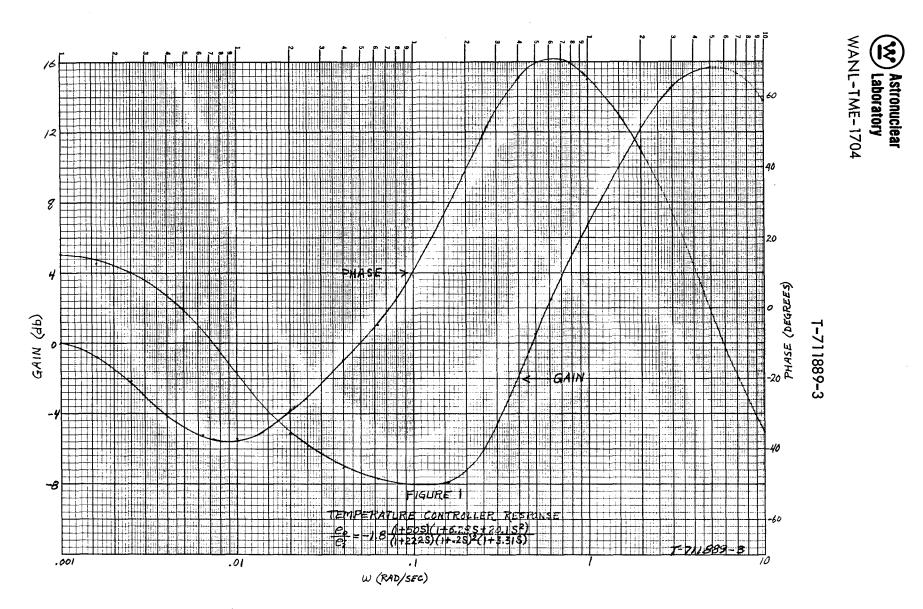


Figure 1

Temperature Controller Response

- 7 -



# ACCEPTANCE TEST SPECIFICATION AND PROCEDURE

Experimental Controller No. 1

Temperature Error Amplifier

# 910E314G01

DATE:

August, 1967

**Circuits Design Equipment Design** 

Date

1.1 lame. 11.

Supervisor, Circuits Design Date Equipment Design

Quality Engineering

Date

Control Systems Engineering Date

INFORMATION CATEGORY

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Authorized Classifier Date

PREPARED BY:

APPROVED BY:



# T-711889-4 ACCEPTANCE TEST SPECIFICATION AND PROCEDURE Experimental Controller No. 1 Temperature Error Amplifier 910E314G01

# 1. SCOPE

This document contains the requirements for the acceptance testing of the Amplifier Circuit Board prior to incorporating the board into the Experimental Controller Chassis.

# 2. REQUIREMENTS

2.1 The acceptance test shall consist of a <u>Visual Examination</u> (to be performed by Quality Control) and a <u>Functional Test</u> (to be performed by Electronics and Instrumentation and witnessed by Quality Control).

2.2 The acceptance test shall be performed in the order of and as specified in the procedure. Discrepancies found during the visual examination shall be corrected and reinspected before performing the functional test. Failure or inability to obtain a required measurement during formal functional testing shall result in establishing a "hold" on the test. The failure or inadequacy shall be recorded by Quality Control and shall be reviewed by the WANL Engineering Review Board (ERB). The equipment shall be repaired and sections of the test repeated as determined by the ERB. Visual examination shall be performed on the reworked or repaired areas before resuming testing.



WANL-TME-1704

# T-711889-4

# 3. APPLICABLE DOCUMENTS

- 3.1 Drawing 910E314 Temperature Error
- 3.2 Drawing 928F960G01 Printed Circuit Board

# 4. EQUIPMENT REQUIRED

4.1 +15+.05 VDC source with +0.05% regulation and 1 mv. max. ripple

4.2 -15+.05 VDC source with +0.05% regulation and 1 mv. max. ripple

4.3 Positive signal source, variable 0-10 VDC with .01% resolution and 1 mv. max. ripple

4.4 Negative signal source, variable 0-10 VDC with .01% resolution and 1 mv. max. ripple

4.5 Model 269 Simpson Ohmmeter or equal

4.6 Digital Voltmeter H-P 3440A or equal

4.7 Set of equipment to measure frequency response and phase shift between .001 cps and 50 cps. (Weston-Boonshaft and Fuchs DA410 or equal)

#### 5. VISUAL EXAMINATION

The equipment under test shall be presented in its final form together with the applicable schematic and assembly drawing. The visual examination shall consist of the following parts:

#### 5.1 WORKMANSHIP, ASSEMBLY, AND FIT

The inspector shall inspect the equipment for workmanship to WANL requirements, and to assure that the overall board is of the proper dimensions per the assembly drawing.

Westinghouse Drawing Number\_\_\_\_\_Rev.\_\_\_\_

Workmanship OK

5.2 MATERIALS, PARTS, AND FINISHES

The equipment shall be inspected to assure that the materials, parts, and finishes are in accordance with the applicable assembly drawings. Incoming inspection records on materials, parts, and finishes shall be utilized to determine conformance to the assembly drawings where possible.

Materials OK\_\_\_\_\_

5.3 MARKING

. . . .

The markings on the equipment shall be inspected to ensure conformance to the applicable drawings and to assure that they are acceptable as to permanence and readibility.

Marking OK



#### 6. FUNCTIONAL TESTS

#### 6.1 RESISTANCE CHECKS

6.1.1 Make the following resistance measurements using the Simpson Model 269 as an ohmmeter.

From	To	Required	Measured
Pin 3	τρι	<1 ohm	
Pin 8	TP2	<1 ohm	
Pin 22	трз	< 1 ohm	
Pin 24	TP4	<1 ohm	
Pin 26	TP5	<li>&lt; 1 ohm</li>	. <u></u>
Pin 22	Pin 24	200K <u>+</u> 5%	
Pin 24	Pin 26	183K <u>+</u> 5%	
Pin 26	TPI	33.7K <u>+</u> 5%	

# 6.2 BALANCE AND DC GAIN CHECK

6.2.1 Apply power to the board. (+15 VDC to Pin 1 and -15 VDC to Pin 2; GND to Pin 3)

6.2.2 Ground Pins 22, 24, and 26 and adjust the voltage offset of A1 for minimum output

(<1 mv.) at Pin 8. Record offset voltage: \_\_\_\_\_. Verify that offset pot < 1/2 turn
from ends: \_\_\_\_\_.</pre>

6.2.3 Measure gain using each input separately with other inputs grounded. Apply +10+.01 VDC inputs and record outputs below:

At Pin 22,  $(\vee = +10+.03)$ At Pin 24,  $(\vee = +10+.03)$ At Pin 26,  $(\vee = +.148+.01)$ 

6.2.4 Apply opposite polarity signals to Pins 22 and 24 of about 5 VDC and equal in magnitude. The output at Pin 8 should be within +20 mv of the difference in magnitudes of the input signals. Record:

Input Voltage to Pin 22 \_\_\_\_\_V

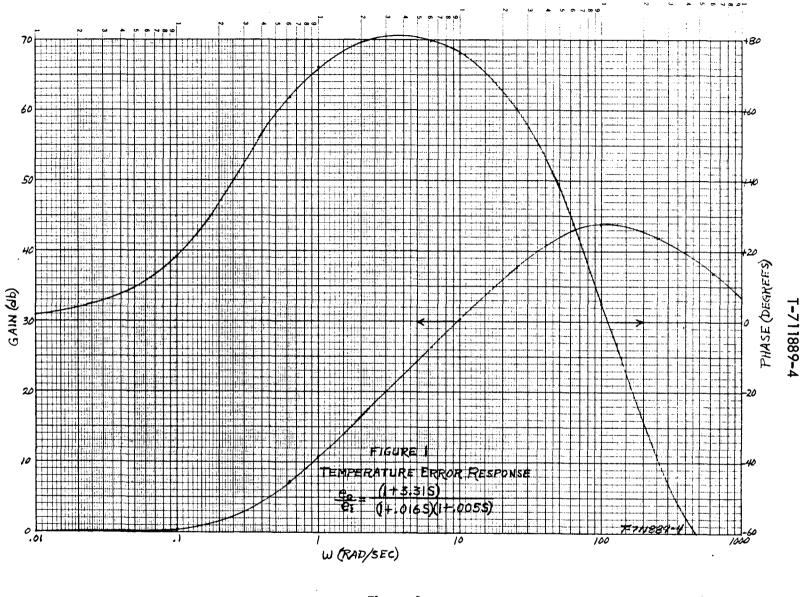
Input Voltage to Pin 24 V

Output Voltage at Pin 8 V

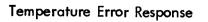
6.3 FREQUENCY RESPONSE CHECK

6.3.1 Determine the frequency response of the amplifier by using Pin 22 for input and grounding Pins 24 and 26. Plot gain in db and phase in degrees on Figure 1. The following tolerances shall be met in the range indicated:

- a) 0.010 ≤ W ≤ 4 rad/sec
   Gain +2db from nominal
   Phase +10<sup>o</sup> from nominal
- b)  $4 \leq W \leq 314 \text{ rad/sec}$ Gain +5db from nominal Phase +20° from nominal







WANL-TME-1704 Astronuclear Laboratory

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# FUNCTIONAL TESTS FOR

# XE-1 Experimental Controller No. 1 ETS-1 938J012G01 TEMPERATURE CONTROLLER CIRCUIT

DATE:

September, 1967

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Circuits Design Equipment Design

Date

longen 9/7/67

APPROVED BY:

PREPARED BY:

Supervisor, Circuits Design Date Equipment Design

E.J. m. Quarde 10.6.67

Quality Engineering

Date

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Control Systems Engineering Date

INFORMATION CATEGORY

Inclass 9/7/67

Authorized Classifier Date



# T-711889-5 FUNCTIONAL TESTS FOR XE-1 Experimental Controller No. 1 ETS-1 TEMPERATURE CONTROLLER CIRCUIT

# 1. SCOPE

This document contains the requirements for the functional tests for the XE-1

Experimental Controller No. 1 Acceptance Test Specification and Procedure, T-711889,

Paragraph 6.1.

# 2. FUNCTIONAL TESTS

# 2.1 RESISTANCE AND CONTINUITY CHECKS

2.1.1 Before applying power to the chassis, make the following resistance checks using the Simpson Model 269:

From (+)	<u>To (-)</u>	Ohms Required	Ohms Measured
J ]-R	ΤΡΙ	< 2 Ohms	
J1-S	TP2	< 2 "	
J1-L	трз	< 2 "	
J1-M	TP4	< 2 "	
J1-A	TP5	<1 "	<u> </u>
J1-B	TP6	<1 "	<u></u>
J1-F	TP7	<1 "	
J1-E	Chassis	<1 "	
A 1 TP3	TP8	<1 "	



From (+)	<u>To (-)</u>	Ohms Required	Ohms Measured
TP7	J3-EE	< 1	
TP7	J3-CC	< 1	
TP7	J3-AA	< 1	
TP7	13- <u>W</u>	< 1	
TP7	J3- <u>Q</u>	< 1	
TP8	J3-FF	$\leq 1$	
TP9	J3-DD	< ۱	
TP10	J3-BB	< 1	
J3- <u>X</u>	J3- <u>P</u>	< 1	
J3- <u>P</u>	TP-12	< 1	

Laboratory WANL-TME-1704 T-711889-5 Ohms Required Chms Measured From (+) To (-) TP9 A 1TP4 < 1 Ohm < 1 н **∧**1TP5 **TP10** < 1 п ATTP2 TP11 **く** 1 11 A2TP3 **TP12** く1 11 AITPI TP7 н < 1 A2TP2 TP11 A2TP1 TP7 < 1 н

2.2 OFFSET ADJUSTMENT, DC GAIN AND LIMIT CHECK

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2.2.1 Apply +15VDC to J1-L, -15VDC to J1-M and Common to J1-F.

2.2.2 Jumper TP8 ( $T_D$ ), TP9 ( $T_M$ ), and TP10 (Freq Anal) to TP7 (Common). Connect the DVM between TP11 ( $T_E$ ) and TP7. Adjust the offset pot on board A1 to obtain a minimum reading on the DVM (  $\leq$  1 mv.). Record offset voltage:

2.2.3 Move the DVM from TP11 to TP12 ( $\Theta_D$ ). Jumper TP11 to TP7. Adjust the offset pot on board A2 to obtain a minimum reading on the DVM (< 1 mv.). Record offset voltage:

2.2.4 Remove the jumpers from between TP8 and TP11 and TP7. Apply a signal to TP8 of approximately 4 VDC of either polarity and measure the output at TP12 with the DVM. Determine the DC gain and record (K = 0.415+.008): \_\_\_\_\_.

2.2.5 Move the jumper to TP9 from TP9 to TP8. Apply a signal to TP9 of approximately 4 VDC with the polarity opposite to that used in Paragraph 2.2.4 and measure the output at TP12 with the DVM. Determine the DC gain and record ( $K = 0.415 \pm .008$ ): \_\_\_\_\_.

2.2.6 Apply positive and negative signals to TP9 of sufficient amplitude to measure the output limits at TP12 and record the voltage limits:

Positive Limit (4+.5VDC)\_\_\_\_\_ Negative Limit (-4+.5VDC)\_\_\_\_\_



WANL-TME-1704

#### T-711889-5

2.2.7 Move the jumper to TP10 from TP10 to TP9. Apply a signal to TP10 of approximately 10VDC of either polarity and measure the output at TP12 with the DVM. Determine the DC gain and record (K = .00616+.00013 \_\_\_\_\_\_. Move jumper to TP8 from TP8 to TP10. 2.2.8 Apply +28VDC to J3-HH and J3-Y and +28VDC return to J3-GG and J3-Z. Apply a signal to TP8 of approximately 2VDC of either polarity and measure the output at TP12 with the DVM five minutes after application of the signal. Determine the DC gain and record (K = 1.80+.036): \_\_\_\_\_\_.

2.3 FREQUENCY RESPONSE CHECK

2.3.1 Apply +28VDC to J3-HH and J3-Y and +28VDC return to J3-GG and J3-Z. Run a frequency response between input TP8 and output TP12 with TP9 and TP10 jumpered to TP7. Plot gain in db and phase in degrees on Figure 1. The following tolerances shall be met in the range indicated:

> .01 rad/sec  $\leq W \leq 4$  rad/sec GAIN +2db from nominal Curve (Figure 1) PHASE +10° from nominal Curve (Figure 1)

#### 2.4 FUSE INDICATOR CHECK

2.4.1 Remove fuses F1 through F5. With the appropriate power supplies energized, fuse indicators F1 through F5 shall illuminate. When the fuses are replaced, the fuse indicators shall go out.



### ACCEPTANCE TEST SPECIFICATION AND PROCEDURE (Checkout Procedure)

#### Experimental Controller No. 1

Drum Override

### 1. SCOPE

This document contains the requirements to functionally checkout the Drum Override on the Experimental Controller No. 1 Chassis (WANL Drawing 938J912, Schematic Diagram WANL Drawing 938J913).

These tests assume the individual P/C cards have been checked per the appropriate Accetpance Test Procedure and all card adjustments have been made per these Acceptance Test Procedures. The functional tests specified are to be performed as chassis checks.

## 2. DRUM OVERRIDE FUNCTIONAL TESTS

The following functional tests are to be performed to confirm proper operation of the Drum Override.

## 2.1 RESISTANCE AND CONTINUITY CHECKS

Before applying power to the chassis, make the following resistance checks:

From (+)	<u>To (-)</u>	Ohms Required	Ohms Measured
J2 <del>-</del> FF	TP14	2 Ohms	
J2-EE	TP7	2 "	



From (+)	<u>To (-)</u>	Ohms Re	quired	Ohms Measured
J2 <b>-</b> K	TP2	2 O	hms	
J2-BB	TP17	2	n	
J2-AA	TP7	2	н	
J2- <u>Z</u>	TP18	2	11	
J2- <u>Y</u>	TP7	2	II	
J2- <u>W</u>	TP19	2	11	
J2 <b>-</b> ⊻	TP7	2	н	
J2- <u>U</u>	TP16	2	н	
J2 <b>-</b> <u>T</u>	TP7	2	11	
J2- <u>Q</u>	TP7	2	11	
J2 <b>-</b> <u>J</u>	TP20	2	11	
J2-1	TP7	2	и	
J2-DD	A5TP6	2	II	
J2-CC	A 5TP6	100	11	
J2- <u>X</u>	A5TP4	2	и	
J2 <del>-</del> HH	A6TP1	2	п	
J2-GG	A6TP1	100	11	
J2 <u>-S</u>	A6TP2	2	II	
J2- <u>P</u>	TP4	2	II.	
J2 <b>-</b> <u>R</u>	A6TP2	2	II	
13- <u>2</u>	A7TP2	2	11	

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From (+)	<u>To (-)</u>	Ohms Requ	ired	Ohms Measured
J3 <b>-</b> <u>T</u>	TP7	2 "		<u> </u>
J3 <b>-</b> U	A6TP6	2 "		
J3- <u>V</u>	A6TP6	100 "		·····
A5TP2	J6-24	2 "		
TP15	A 3TP6	2 "		

Connect Ohmmeter between A3TP6 and A3TP8 of the "Rate Limited Tracker" checkout card. Adjust A3R7 to CCW position

Adjust R1, "Rate Clamp Adjust", to 500 divisions (mid-range).

Apply power to the chassis.

## 2.2 BUFFER AMPLIFIER CHECKS

This test checks the proper operation of the buffered drum demand signal to the drums error meter, the buffered manual drum position signal, and the manual drums followup demand.

2.2.1 Connect a +5.00VDC voltage source between TP14 and TP7, the buffered drum demand input. Measure the output voltage between A7TP2 and TP7, the drums error meter output. This voltage should be +5.00+.1VDC.

Voltage between A7TP2 and TP7 VDC

Measure the output voltage between TP16 and TP7, the manual drums followup demand output. This voltage should be +5.00+.1 VDC.

Voltage between TP16 and TP7 VDC



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#### T-711889-6

2.2.2 Connect a +5.00 VDC voltage source between TP19 and TP7, the manual drums position demand input. Measure the output between TP20 and TP7, the drum override position demand. This voltage should be -5.00+.1 VDC.

Voltage between TP20 and TP7 VDC

2.3 RATE CLAMP ACTIVATE CIRCUIT

This test checks the proper pickup of the "Rate Clamp Activate" Relay, A5K1, the latching of this relay, and the unlatching of A5K1.

2.3.1 Connect a +5 VDC voltage source between TP18 and TP7, the Auto Startup Exponential Setpoint input. Connect a +5.50 VDC voltage source between TP14 and TP7, the the Buffered Drums Demand input. Measure resistance between A5TP4 and J2-<u>M</u>. This resistance should be less than 2 ohms.

Ohms

Remove the Checkout Card A3 and measure the resistance from TP15 to J6-4. This resistance should be < 2 ohms.

Ohms

2.3.2 Disconnect voltage source from TP14. Measure the resistance between A5TP4 and J2-M. This impedance should be <2 ohms.

2.3.3 Connect +28 VDC voltage source between J3-U and J3-V, the Engine Reset input.

Measure the resistance between A5TP4 and J2-M. This resistance should be >100 megohms.

Ohms

Insert Card A3.



### 2.4 DRUM OVERRIDE NORMAL/OPERATE CIRCUIT

This test checks the proper operation of the Drum Override Circuit, "Rate Limited Tracker" card and the pickup, latching and unlatching of the drum override normal/operate function.

2.4.1 Connect checkout circuit as shown in Figure 1.

2.4.2 Connect a DVM between TP13 and TP7. Adjust R1 "Rate Clamp Adjust" until the DVM reads -3.2 VDC (1.25°/sec).

DVM Reading

2.4.3 Remove Card A3

2.4.4 Connect DVM between TP17 and TP7. Adjust 5K external pot until DVM reads -4.29 VDC.

\_\_\_\_\_ DVM Reading

- 2.4.5 Connect +5.00 VDC (90°) to TP16 by closing S2.
- 2.4.6 Connect +5.50 VDC (99°) to TP14 by closing S3.

Verify DVM connected as in Figure 1 reads +10VDC

2.4.7 Close and Open S1. Verify DVM reads +10VDC

2.4.8 Open S3. Verify DVM read 0

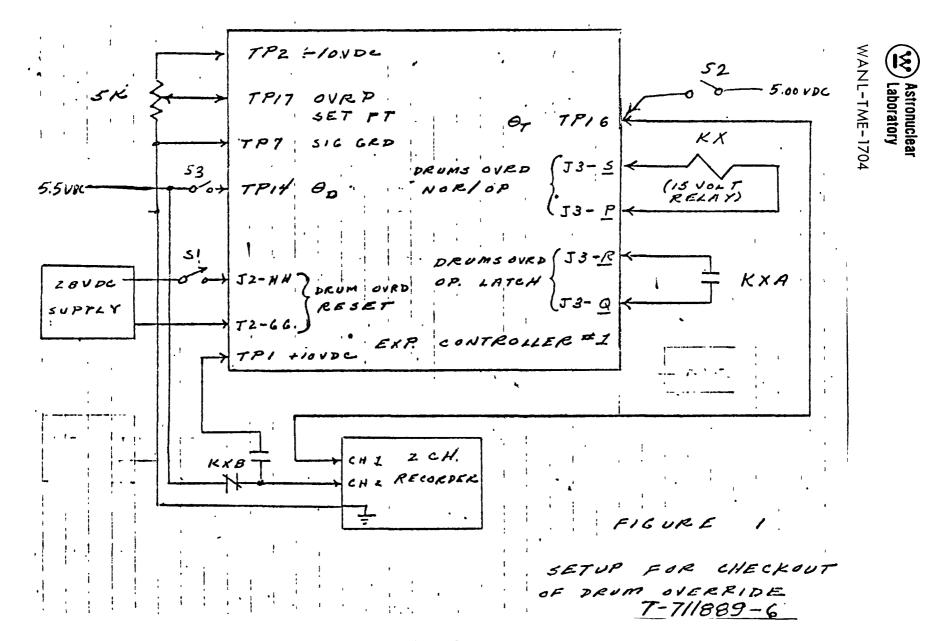


Figure 1 Setup for Checkout of Drum Override

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# T-711883-5

### ACCEPTANCE TEST SPECIFICATION AND PROCEDURE

## Relay Module, 4PDT, 2 Unit

### 979D576G01-G02

DATE:

September, 1967

walcheek i-26-67

Circuits Design Equipment Design

Date

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APPROVED BY:

PREPARED BY:

Supervisor, Circuits Design Date Equipment Design

10 R (] Quality Engineering Date

2741 C. C. Maria

Control Systems Engineering Date

INFORMATION CATEGORY

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Authorized Classifier Date

### T-711883-5 ACCEPTANCE TEST SPECIFICATION AND PROCEDURE Relay Module, 4PDT, 2 Unit 979D576G01-G02

# 1. SCOPE

This document contains the requirements for the acceptance testing of the Relay Module Circuit Board prior to incorporating the board into a chassis.

# 2. REQUIREMENTS

2.1 The acceptance test shall consist of a <u>Visual Examination</u> (to be performed by Quality Control) and a <u>Functional Test</u> (to be performed by Electronics and Instrumentation and witnessed by Quality Control).

2.2 The acceptance test shall be performed in the order of and as specified in the procedure. Discrepancies found during the visual examination shall be corrected and reinspected before performing the functional test. Failure or inability to obtain a required measurement during formal functional testing shall result in establishing a "hold" on the test. The failure or inadequacy shall be recorded by Quality Control and shall be reviewed by the WANL Engineering Review Board (ERB). The equipment shall be repaired and sections of the test repeated as determined by the ERB. Visual examination shall be performed on the reworked or repaired areas before resuming testing.

T-711883-5



# 3. APPLICABLE DOCUMENTS

- 3.1 Drawing 979D576 Relay Module, 4PDT, 2 Unit
- 3.2 Drawing 928F423 Printed Circuit Board
- 3.3 Drawing 979D575 Schematic, Relay Module

### 4. EQUIPMENT REQUIRED

- 4.1 Model 269 Simpson Ohmmeter or equal
- 4.2 +15+1 VDC Power Source

### T-711883-5

#### 5. VISUAL EXAMINATION

The equipment under test shall be presented in its final form together with the applicable schematic and assembly drawing. The visual examination shall consist of the following parts:

# 5.1 WORKMANSHIP, ASSEMBLY, AND FIT

The inspector shall inspect the equipment for workmanship to WANL requirements,

and to assure that the overall board is of the proper dimensions per the assembly drawing.

Westinghouse Drawing Number\_\_\_\_\_Rev.\_\_\_\_

Workmanship OK \_\_\_\_\_

5.2 MATERIALS, PARTS, AND FINISHES

The equipment shall be inspected to assure that the materials, parts, and finishes are in accordance with the applicable assembly drawings. Incoming inspection records on materials, parts, and finishes shall be utilized to determine conformance to the assembly drawings where possible.

Materials OK\_\_\_\_\_

5.3 MARKING

The markings on the equipment shall be inspected to ensure conformance to the applicable drawings and to assure that they are acceptable as to permanence and readibility.

Marking OK\_\_\_\_\_

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# 6. FUNCTIONAL TESTS

# 6.1 RESISTANCE CHECK - RELAY DE-ENERGIZED

# 6.1.1 Make the following resistance checks:

From (+)	To (-)	Ohms	Check
TP1	Pin 4	< 1	
TP2	Pin 3	< 1	
TP3	Pin 5	< 1	
TP4	Pin 13	< 1	
TP5	Pin 11	< 1	
TP6	Pin 25	< 1	·····
TP7	Pin 24	< 1	
TP8	Pin 26	< 1	
TP9	Pin 34	< 1	
TP10	Pin 32	< 1	
Pin 4	Pin 12	500 <u>+</u> 10%(G01)	
Pin 4	Pin 12	206 <u>+</u> 10%(G02)	
*Pin 12	Pin 4	< 30	
Pin 3	Pin 2	> 100 Meg	
Pin 3	Pin 7	< 1	
Pin 5	Pin 6	> 100 Meg	
Pin 5	Pin 8	< 1	
P <b>i</b> n 1 <b>3</b>	Pin 14	> 100 Meg	
Pin 13	Pin 1	< 1	
Pin 11	Pin 10	> 100 Meg	
Pin 11	Pin 9	< 1	
Pin 25	Pin 33	500 <u>+</u> 10%	- <u></u>
*Pin 33	Pin 25	< 30	

Astronuclear Laboratory WANL-TME-1704

# T-711883-5

From (+)	<u>To (-)</u>	Ohms	Check
Pin 24	Pin 23	> 100 Meg	
Pin 24	Pin 28	< 1	
Pin 26	Pin 27	> 100 Meg	
Pin 26	Pin 29	< 1	
Pin 34	Pin 35	> 100 Meg	
Pin 34	Pin 22	< 1	
Pin 32	Pin 31	> 100 Meg	
Pin 32	Pin 30	< 1	

\*Use X1 scale on Ohmmeter.

T-711883-5

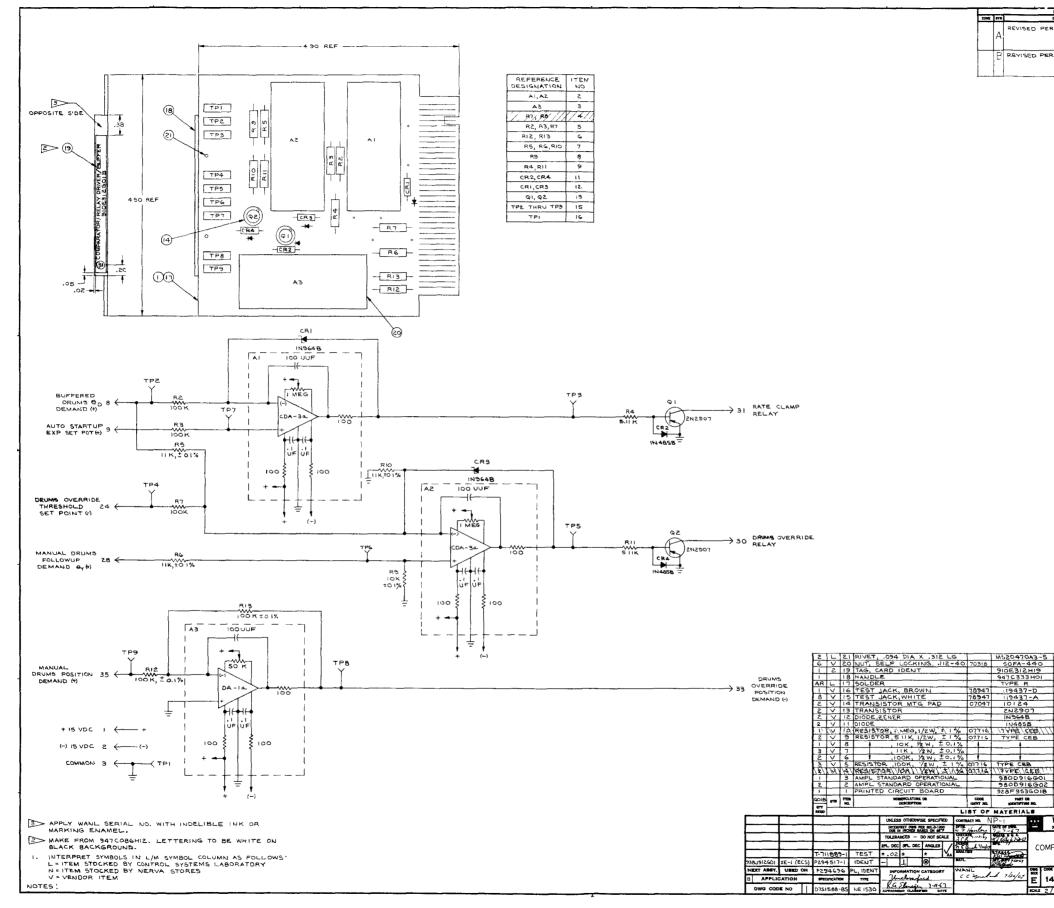


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# 6.2 RESISTANCE CHECK - RELAY ENERGIZED

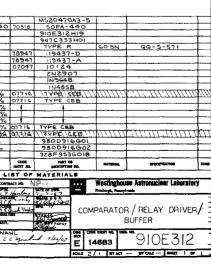
- 6.2.1 Ground Pin 12 and Pin 33.
- 6.2.2 Energize Relays K1 and K2 by applying +15 VDC to Pin 4 and Pin 25.
- 6.2.3 Make the following resistance checks:

From	To	Ohms	Check
Pin 3	Pin 2	< 1	
Pin 3	Pin 7	> 100 Meg	
Pin 5	Pin 6	< 1	
Pin 5	Pin 8	> 100 Meg	
Pin 13	Pin 14	< 1	····
Pin 13	Pin 1	> 100 Meg	
Pin 11	Pin 10	< 1	
Pin 11	Pin 9	> 100 Meg	
Pin 24	Pin 23	< 1	*** 8
Pin 24	Pin 28	> 100 Meg	
Pin 26	Pin 27	< 1	
Pin 26	Pin 29	> 100 Meg	
Pin 34	Pin 35	< 1	
Pin 34	Pin 22	> 100 Meg	
Pin 32	Pin 31	< 1	
Pin 32	Pin 30	> 100 Meg	

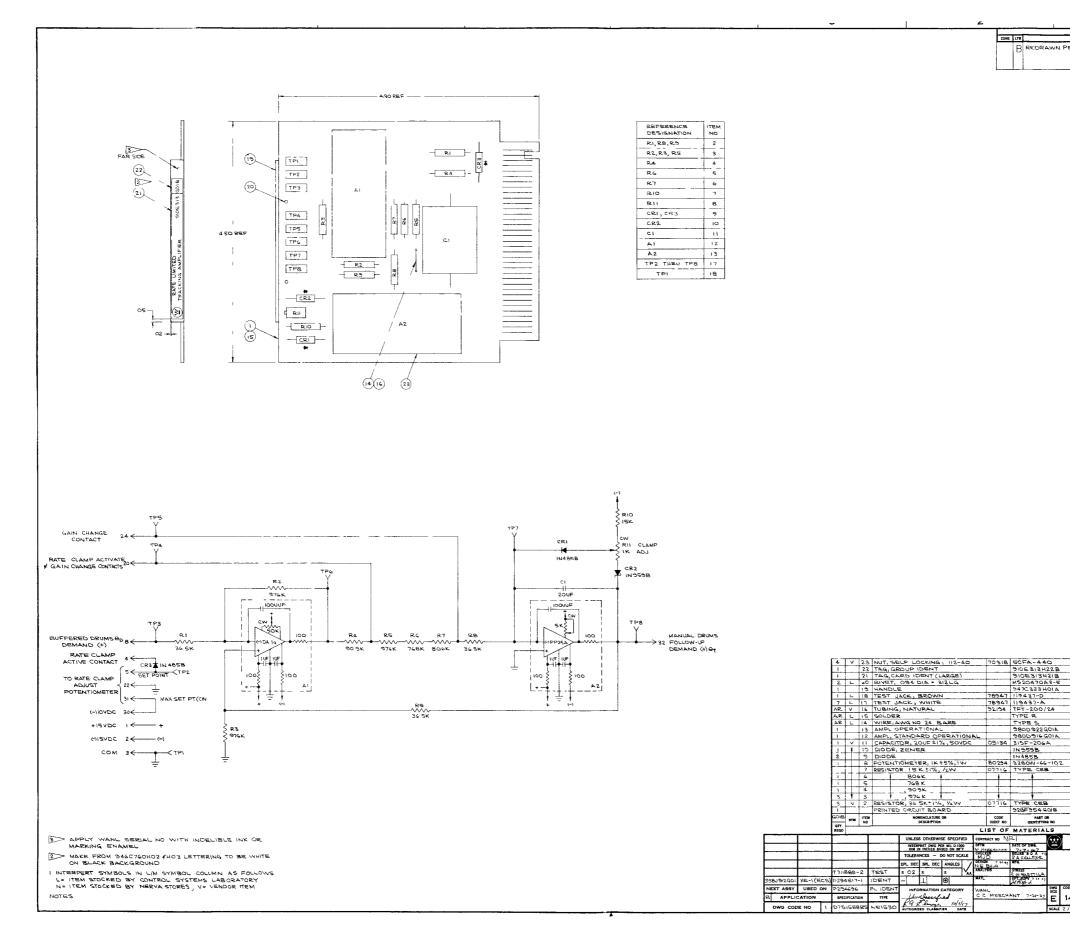


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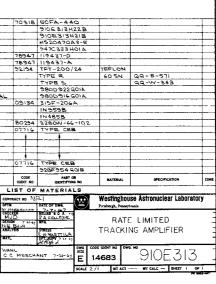


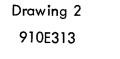
Drawing 1 910E312 Comparator/Relay Driver/Buffer



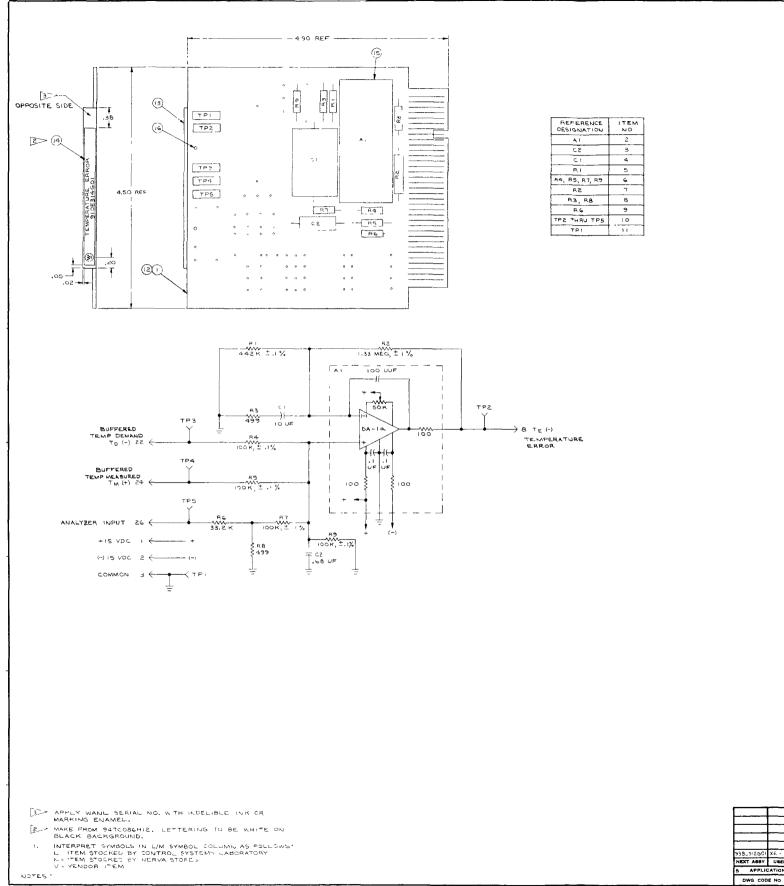
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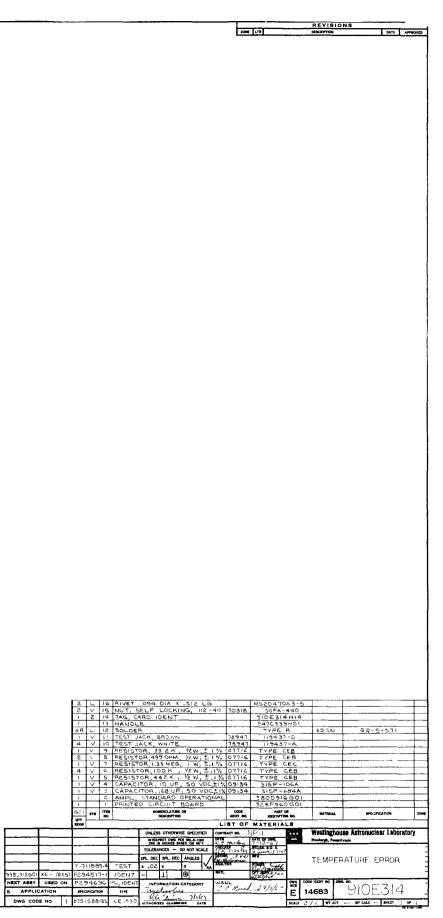






Rate Limited Tracking Amplifier



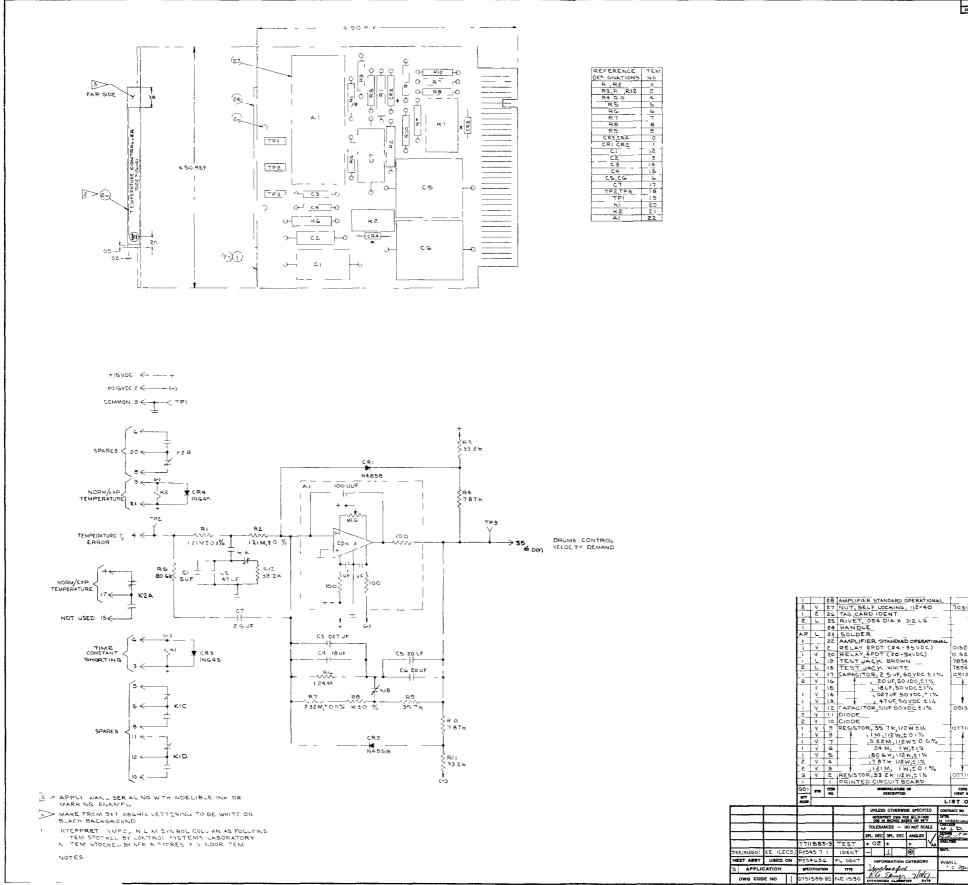


Drawing 3 910E314

Astronuclear Laboratory

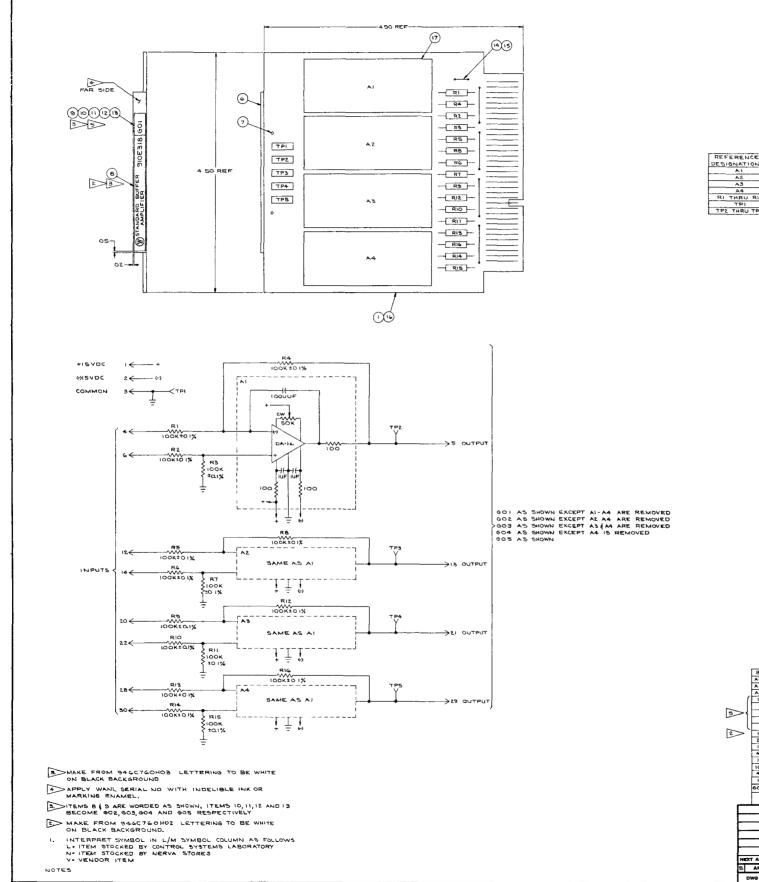
WANL-TME-1704

Temperature Error Amplifier



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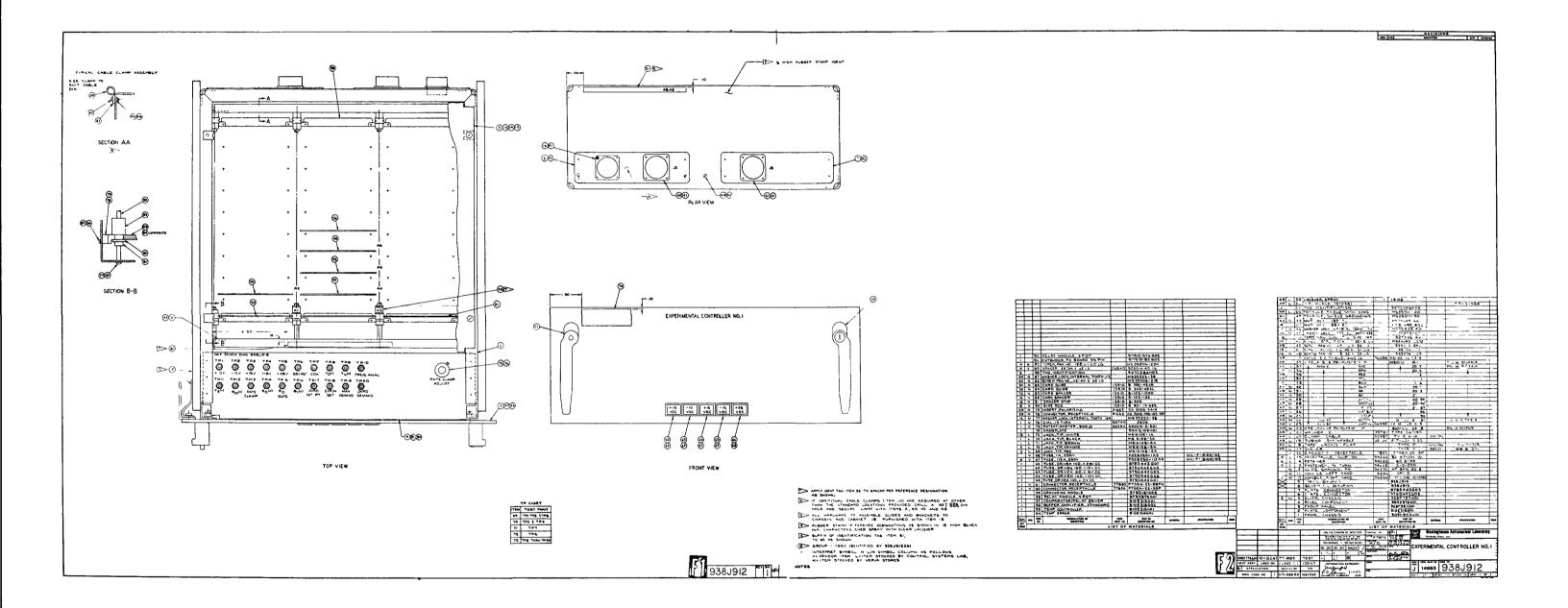
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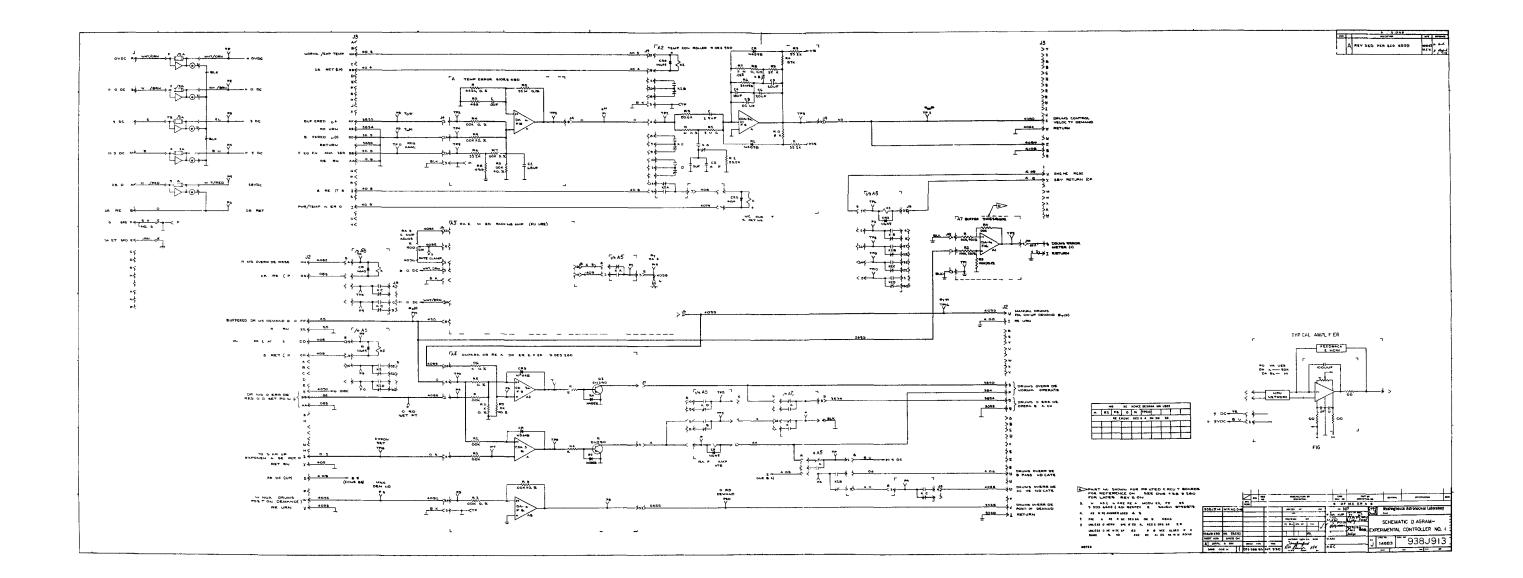




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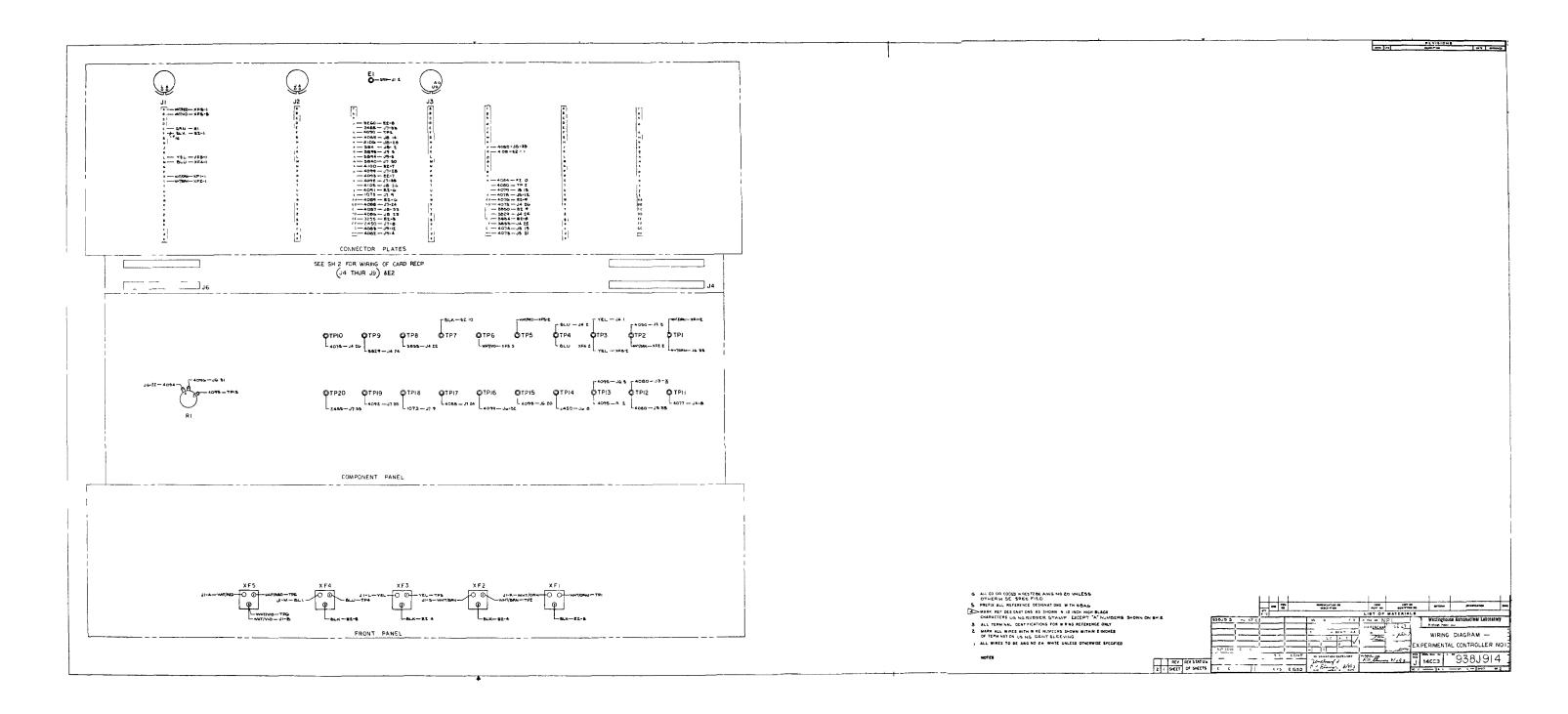


Drawing 6 938J912 Experimental Controller No. 1



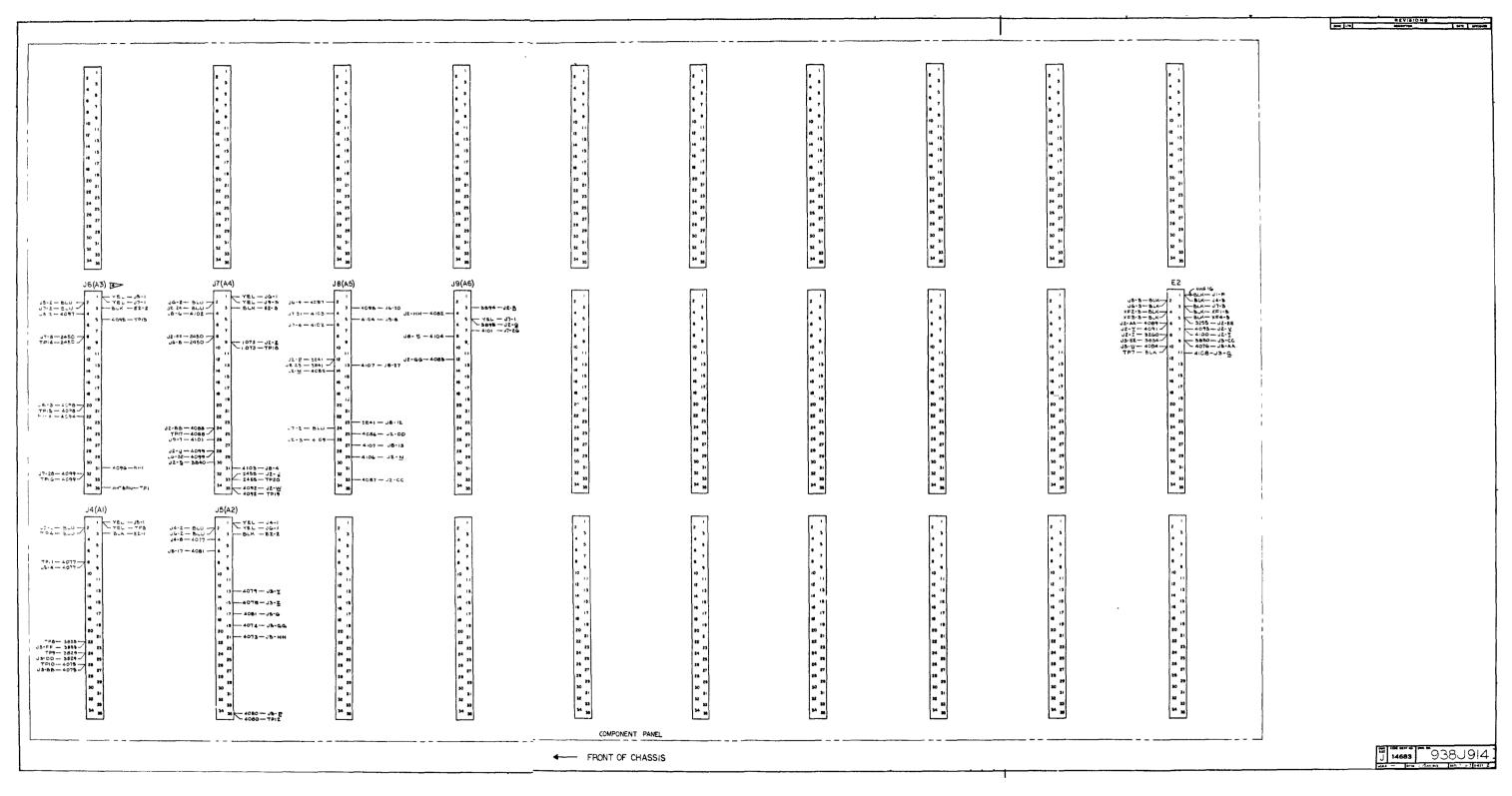


Drawing 7 938J913 Schematic Diagram – Experimental Controller No. 1





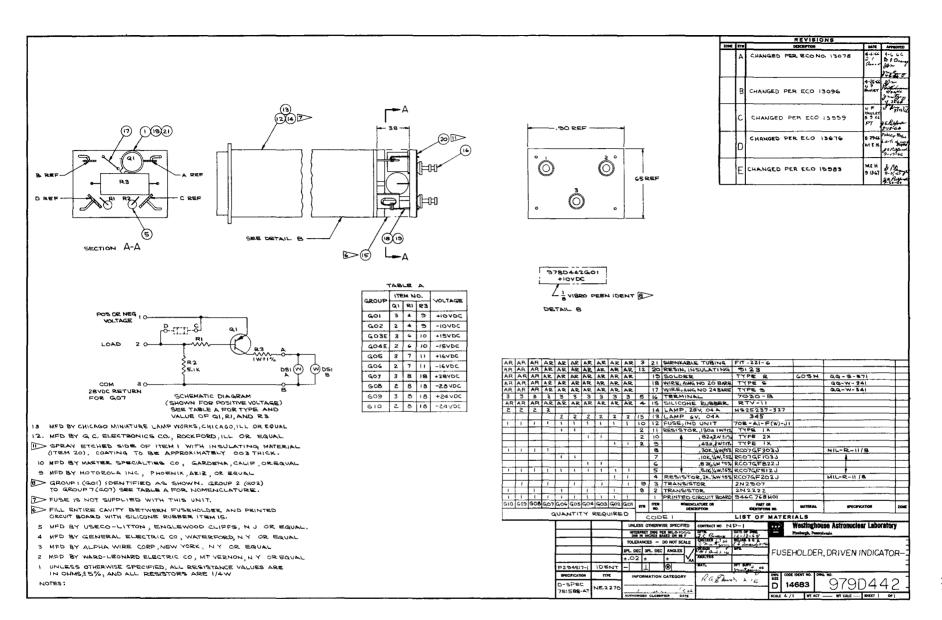
Drawing 8 938J914 Wiring Diagram – Experimental Controller No. 1 (Sheet <u>1</u>)





938J914

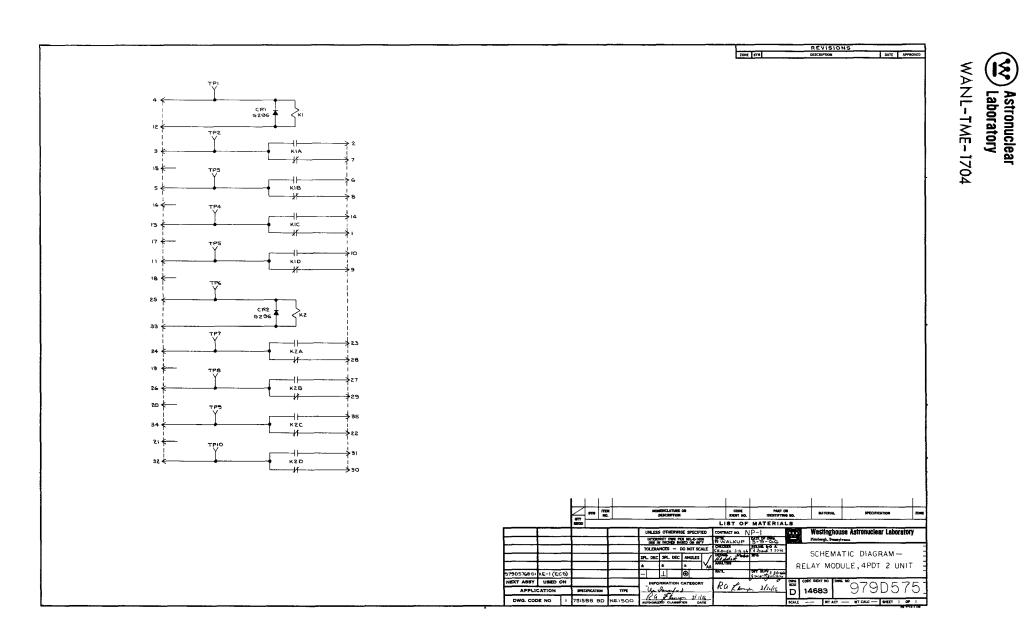
Wiring Diagram – Experimental Controller No. 1 (Sheet <u>2</u>)



979D442

Fuseholder, Driven Indicator

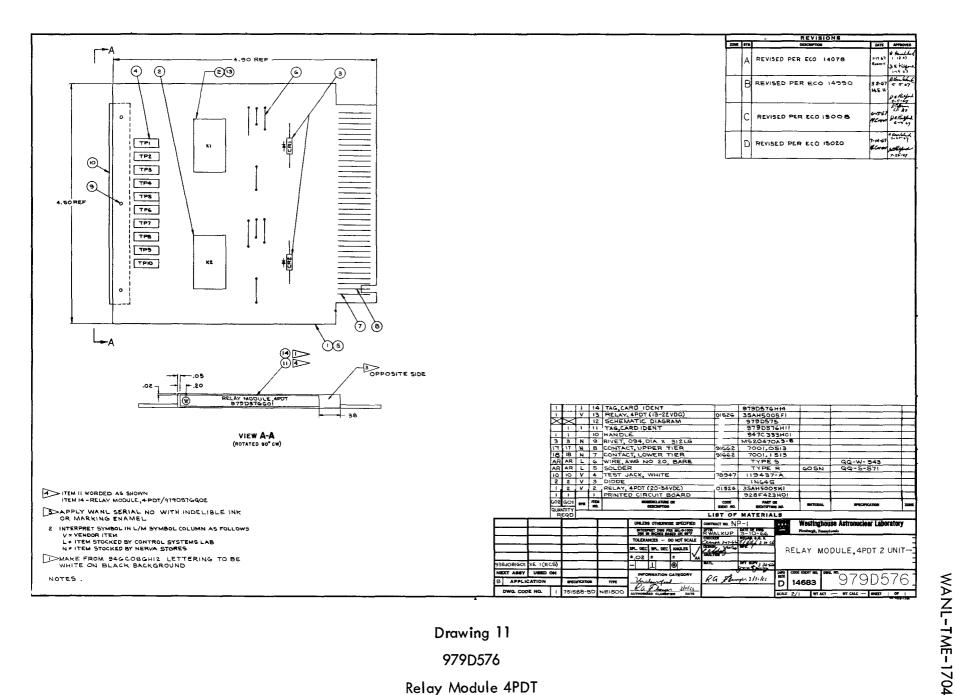
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Drawing 10

979D575

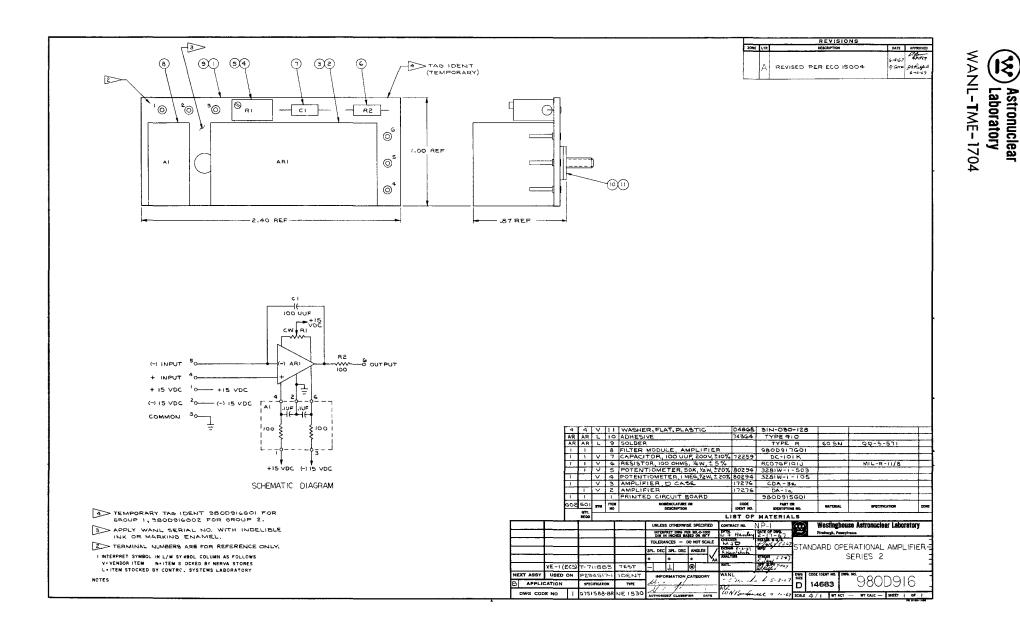
Schematic Diagram, Relay Module 4PDT



979D576

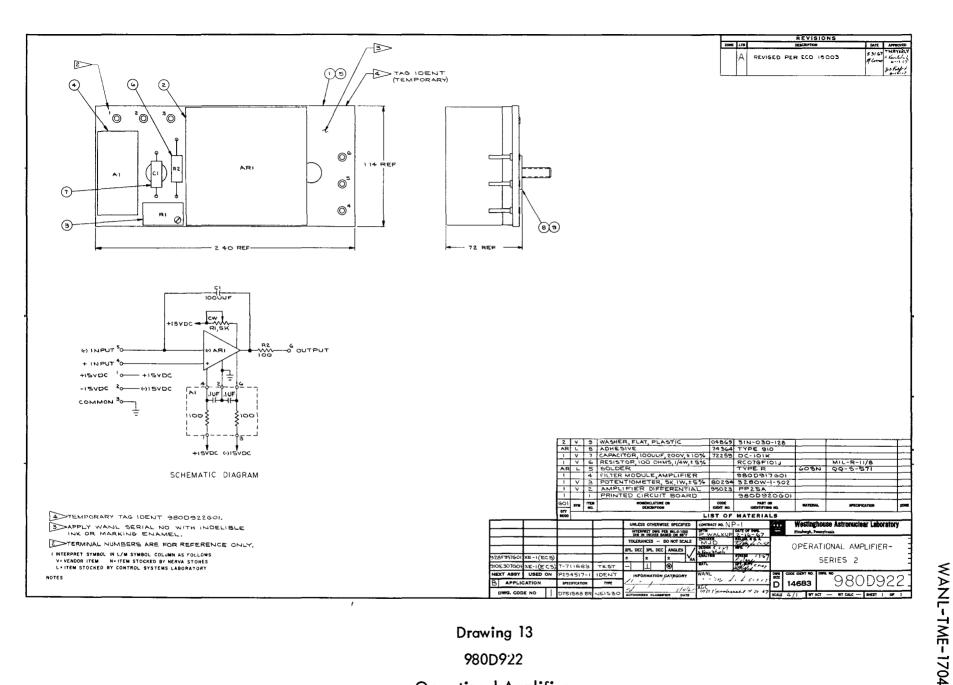
Relay Module 4PDT

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980D916

Standard Operational Amplifier

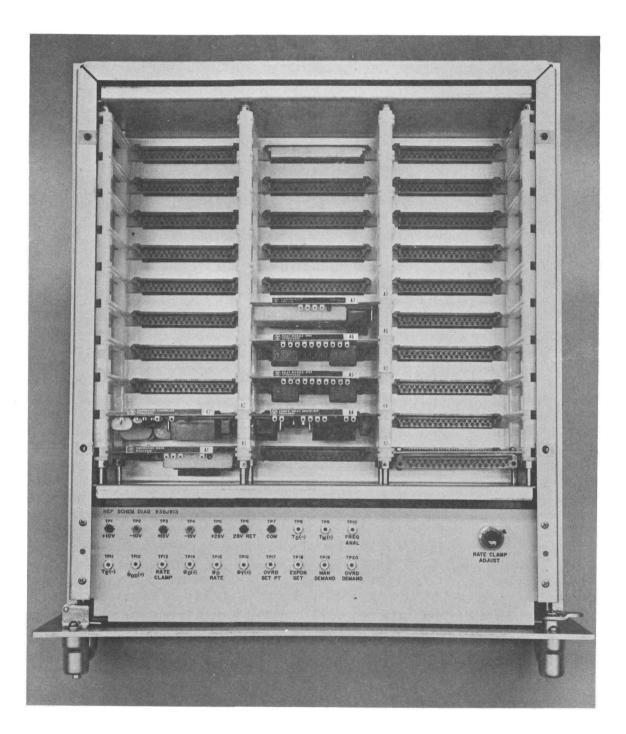


980D922

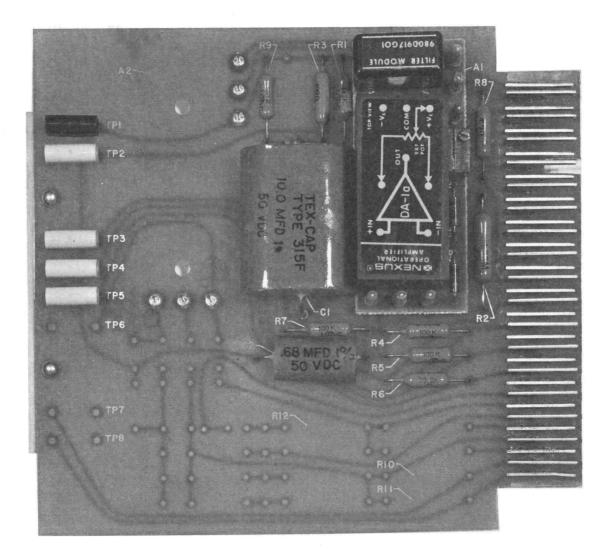
**Operational Amplifier** 



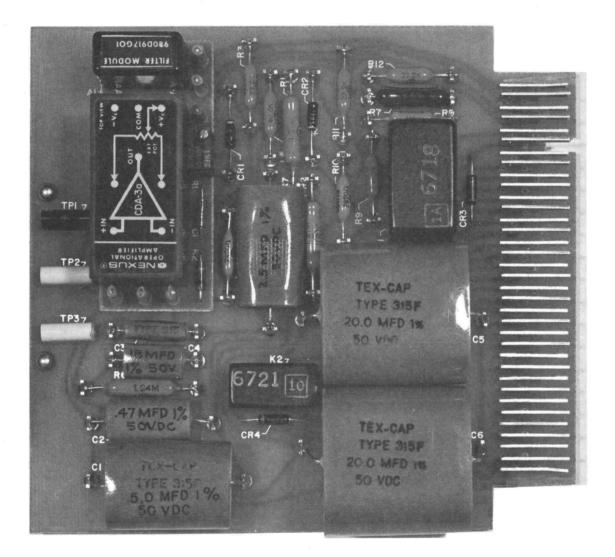




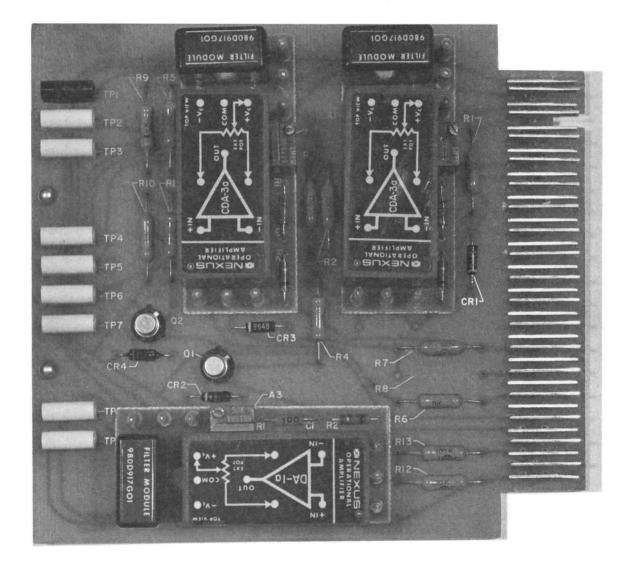






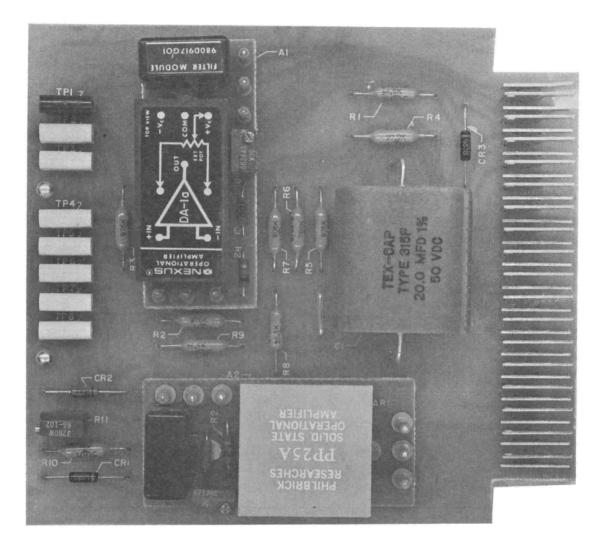




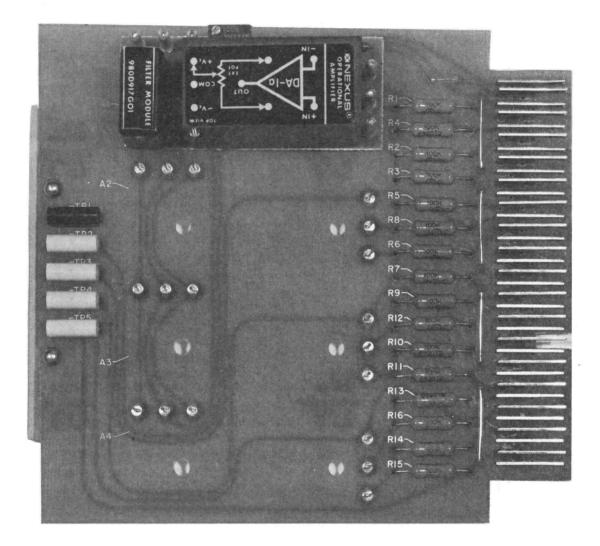














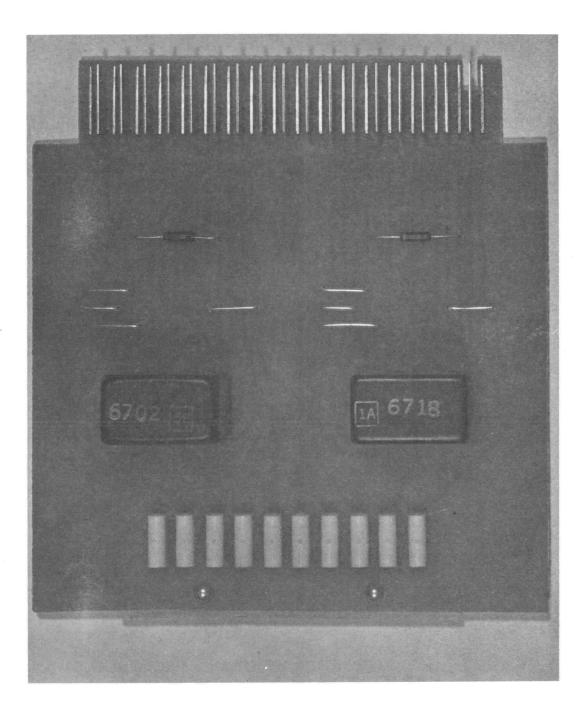


Figure 7 Relay Module RECEIVED 1967 DEG 12 PM 2: 34 SNPO-C CLEVELAND, OHIO

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